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MONTE CARLO METHOD FOR THE CALCULATION OF TRANSPORT PROPERTIES IN A LOW-DENSITY IONIZED GAS

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NATIONAL AERONAUTICS AND SPACE ADMINISTRATION

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by Charles M. Goldstein
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SUMMARY

An introduction to the general Monte Carlo method is presented, along with a discussion of its scope of application to plasma physics. This is followed with a heuristic sketch of the method. The problem of electron flow through a perfect Lorentzian gas in a parallel-plane diode is then formulated. The Monte Carlo solution is discussed in detail along with the relevant computational techniques employed. (Pertinent concepts from the theory of random variables are included in an appendix.)

The effects of mean free path on current-voltage characteristics, density distribution, and potential distribution are presented for two cases - monoenergetic and thermionic emission. Results indicate that electron-neutral elastic collisions can have a significant effect on the current-voltage characteristics for electrode separations as small as one mean free path in the case of thermionic emission, and one-half mean free path in the case of monoenergetic emission.

INTRODUCTION

A major difficulty in the study of low-density ionized gases is the lack of suitable analytical methods for determining the effects of collisions. "Low density" is here defined as those situations in which a characteristic dimension is of the order of a few mean free paths, that is, the regime wherein neither a collisionless nor a continuum approximation can be expected to represent the actual situation. This regime is of importance in low-pressure thermionic diodes, plasma sheaths (probe theory), ion engines, and cross-section measurements.

Much effort has been expended to obtain solutions of the Boltzmann transport equation for low-density neutral gases (ref. 1). Little work has been done on the extension of these methods to low-density ionized gases. Recently, however, Sockol

(ref. 2) has succeeded in numerically integrating the Boltzmann transport equation for a particular low-density ionized gas problem. Unfortunately, the numerical integration is very difficult for even the simplest hard-sphere collision cross section; the feasibility of extending this method for more complex collision cross sections has not as yet been investigated.

This report presents a new method for determining analytically the transport properties in a low-density ionized gas for an arbitrary collision cross section. Results with this method are given for two electron transport problems. The method proposed is, essentially, a consistent-field Monte Carlo method. Since the Monte Carlo method has not been widely applied in the fields of plasma physics or ionized gases, a brief introduction is presented; a review of the pertinent random variable theory is given in appendix A. The ability to use this method effectively is strongly dependent on numerical procedures and "tricks of the trade." A section is therefore included on the various computing techniques; in addition, a complete program listing plus selected flow charts are to be found in appendix C. A discussion of two important computing programs is presented by their author, H. Renkel, in appendix B.

The general method of calculating transport properties is applied herein to the problem of electron transport in a perfect Lorentzian gas with a hard-sphere collision cross section; in particular, the method is employed to obtain electron flux characteristics in a plane-parallel diode including the effect of electron-neutral collisions.

Langmuir (ref. 3) published the first correct solution to the effect of space charge and initial velocities on the potential distribution and thermionic current between parallel-plane electrodes for no collisions (vacuum diode). He also studied (ref. 4) the problem of diffusion of electrons back to the emitter for the case of a very small mean free path. These results are extended herein to the case of electron-neutral collisions for which the mean free path is not necessarily small with respect to the interelectrode separation.

MONTE CARLO METHOD

General Description

The Monte Carlo method is, in general terms, a technique for solving physical and mathematical problems by using random sampling. Although the term "Monte Carlo method" has been subjected to various interpretations, an acceptable statement of the method as applied herein has been given by Donsker and Kac (ref. 5): "The Monte Carlo

approach consists in permitting a 'particle' to play a game of chance, the rules of the game being such that the actual deterministic and random features of the physical process are step by step exactly imitated by the game. By considering very large numbers of particles, one can answer such questions as the distribution of the particles at the end of a certain period of time, the number of particles to escape through a shield of a specific thickness, etc. One important characteristic of the preceding approach is that the functional equation describing the diffusion process is bypassed completely, the probability model used being derived from the process itself. "

A short history of Monte Carlo applications is to be found in the paper by Goertzel and Kalos (ref. 6). An excellent review of the basic principles is given in reference 7, and an extensive bibliography has recently been compiled by Kraft and Wensrich (ref. 8). This method has, in recent years, been employed with considerable success to a wide variety of problems, most notably in the area of nuclear shielding problems (viz., neutron transport). These latter problems are linear in the sense that the neutron trajectories are independent of the neutron density. More recently, the method has been extended to certain nonlinear problems in radiation transport (ref. 9).

There have been some applications of the Monte Carlo methods to the investigation of one-dimensional electron (ion) diodes, but these studies are more often referred to as computer-simulated solutions, or "computer experiments." The difference in terminology reflects the fact that these studies approximate the physical model by a finite number of current sheets, which are then followed deterministically through all mutual interactions by the computer. The Monte Carlo method, on the other hand, most frequently implies repeated, stochastically independent trials. A short history of the aforementioned computer experiments is to be found in the paper by Burger (ref. 10). These studies do not take collisions into account, nor does it seem practical to do so because of the demands this type of analysis would impose on computer storage requirements.

Itoh and Musha (ref. 11) employed a Monte Carlo calculation to determine the ionization and excitation coefficients of electrons in a uniform electric field E for given gas pressure P . They also computed drift velocity and mean energy for several values of E/P . Although the authors state that this method can be extended to strong, non-uniform electric fields, it cannot provide a suitable model from which diode characteristics could be obtained since space-charge effects, which introduce a nonlinearity, have not been considered.

Just as the nonlinearity in the radiation transport problem is characterized by a single parameter, the temperature (ref. 9), so the nonlinearity in the charge-particle transport problems is characterized by the potential. Unlike the photons in the former problems, however, the charged particles experience a body force proportional to the first derivative of the potential.

Heuristic Sketch of the Method

First the relatively simple problem of the attenuation of a molecular beam by a homogeneous gas shall be considered. If the actual experiment is performed for a given emission flux Γ_0 and the flux reaching the target (or collector) Γ_c is measured, it is reasonable to interpret the ratio Γ_c/Γ_0 as the probability that a unit of emitted flux will reach the target. If a knowledge of the scattering probabilities of a single molecule passing through the same gas is assumed, it is possible on a computer to follow a certain number N_0 , one at a time, and tally the number N_c that reach the collector (the others are scattered back to the emitter). Then the ratio N_c/N_0 would be an approximation to the experimentally determined Γ_c/Γ_0 . Since the experimental fluxes may be of the order of 10^{18} particles per square centimeter per second or higher, it is not conceivable, even in this relatively simple situation, to "do the experiment" on the computer. As N_0 becomes larger, however, the approximation N_c/N_0 becomes better. Statistical analysis provides a means of estimating how good the approximation is.

For the case of charged particles flowing through a gas, the situation is complicated by the nonlinearity introduced by the space charge. That is, the flow of charged particles is not only influenced by collisions with the gas molecules, but also by the potential field; the potential field, itself, is a function of the density of charged particles. This is the situation considered herein. To start, for a given collector potential $\mathcal{V}(L)$ a potential distribution $\mathcal{V}(x)$ is assumed. An approximation to the current reaching the collector, N_c/N_0 , is then obtained as in the molecular beam case. In addition, however, the contribution to the density, at preselected data points, of each charged particle is also tallied. These densities are used to solve Poisson's equation for a new potential distribution. The process is then repeated (i.e., iteration is performed on the potential distribution) until the potential distribution "converges." Convergence must here be considered only in a statistical sense; when further iterations produce only random fluctuations in the potential distribution, "convergence" is assumed. Random fluctuations are, of course, to be expected, since only a small statistical sample N_0 of the total flux is considered. After convergence has been achieved, succeeding iterations may be considered, in the parlance of statistical analysis, as independent trials; each resulting approximation N_c/N_0 may be considered a sample mean (appendix A). An analysis of the sample means provides a way of estimating the accuracy of the result.

FORMULATION OF ELECTRON DIODE PROBLEM

The physical model of an infinite parallel-plate diode is depicted in figure 1. In the same figure the types of scattering that may occur for a monotonic potential distribution

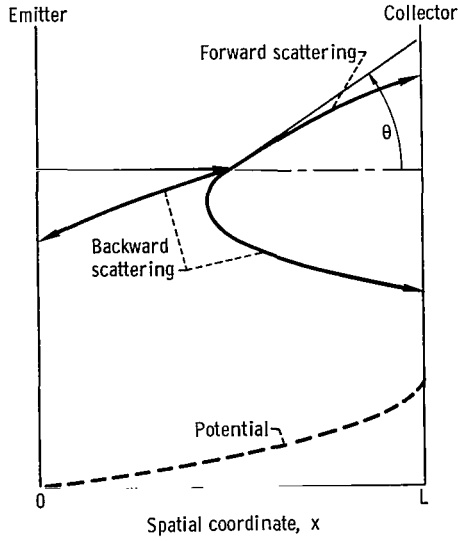


Figure 1. - Diode model and types of scatter.

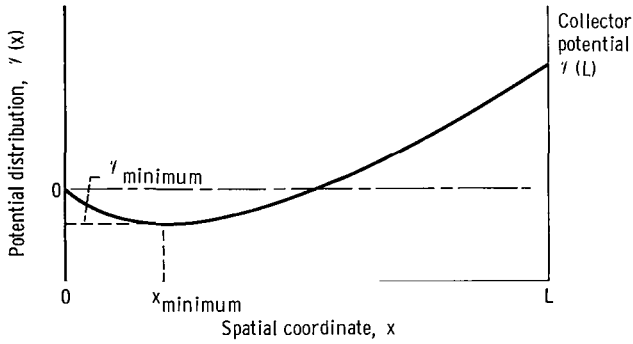


Figure 2. - General potential distribution.

are shown. In figure 2 a typical potential distribution is shown. When a potential minimum exists as indicated in this figure, a certain portion of thermionically emitted electrons will be rejected back to the emitter even in the absence of collisions. The existence of a potential minimum less than both emitter and collector potentials defines the space-charge-limited regime of diode operation.

The perfect Lorentzian gas assumption implies an infinite mass target particle, and hence the laboratory system becomes equivalent to the center of mass system. Since hard-sphere collisions result in isotropic scattering in the center of mass system, the equivalence of the two systems in this case results in isotropic scattering in the laboratory system.

Isotropic scattering means, by definition, that the probability of scattering into unit solid angle is the same for all angles. The probability distribution function (hereafter, p.d.f., see appendix A) is therefore the constant $1/4\pi$. Hence the probability of scattering into solid angle

$d\Omega$ is $d\Omega/4\pi$. In terms of the scattering angle θ , this becomes

$$\frac{d\Omega}{4\pi} = \frac{\sin \theta}{2} d\theta \quad (1)$$

Consequently, the p.d.f. of scattering into angle $d\theta$ is simply $\sin \theta/2$.

The assumption of hard-sphere collisions also implies a constant mean free path λ . Now if that group of electrons that has just collided is considered, then the fraction of these electrons that will suffer collisions in distance ℓ_c is (ref. 12, p. 102, eq. (98a))

$$1 - e^{-\alpha \ell_c} \quad (2)$$

where

$$\left. \begin{aligned} \ell &\equiv s/L \\ \alpha &\equiv L/\lambda \end{aligned} \right\} \quad (3)$$

and s is the path length and L the electrode spacing.

Thermionic Emission

For this case it is assumed that electrons are emitted with a half-Maxwellian velocity distribution

$$f(u, V) du dV = (4/\sqrt{\pi}) V e^{-(u^2 + V^2)} du dV \quad (4)$$

where

$$\left. \begin{aligned} u &\equiv v_x / \sqrt{2kT/m} \\ V &\equiv \frac{\sqrt{v_y^2 + v_z^2}}{\sqrt{2kT/m}} \end{aligned} \right\} \quad (5)$$

The one-dimensional Poisson's equation, in dimensionless variables, becomes

$$\varphi''(y) = C n(y) \quad (6)$$

where

$$\left. \begin{aligned} y &\equiv \frac{x}{L} \\ \varphi &\equiv \frac{eV}{kT} \\ n &\equiv \frac{\hat{n}}{n_0} \end{aligned} \right\} \quad (7)$$

and

$$C = 8(\pi/2kT)^{3/2} m^{1/2} e J_0 L^2 \quad (8)$$

Monoenergetic Emission

The analysis for monoenergetic emission directly parallels that for thermionic collision with a few minor changes. The dimensionless variables u , V , and φ are now defined as

$$\left. \begin{aligned} u &= \frac{v_x}{v_0} \\ V &= \frac{\sqrt{v_y^2 + v_z^2}}{v_0} \\ \varphi &= \frac{2eV}{mv_0^2} \end{aligned} \right\} \quad (9)$$

The constant parameter C in Poisson's equation (eq. (6)) becomes

$$C = \frac{8\pi e L^2 J_0}{mv_0^3} \quad (10)$$

MONTE CARLO SOLUTION

Thermionic Emission

Initial conditions. - It must be emphasized that the test "electrons" are not chosen from the half-Maxwellian distribution (eq. (4)). Although test "electrons" are mentioned, the statistics are obtained for units of electron flux - not units of charge. Hence, the initial velocities must be chosen from the distribution of flux in velocity space

$$\sqrt{\pi} u f(u, V) du dV = 4u V e^{-(u^2 + V^2)} du dV \quad (11)$$

from equation (4). Since the u and V components of velocity are independent, the respective marginal distributions (see ref. 13, p. 287) $F_u(V)$ and $F_V(u)$ can be obtained:

$$F_u(V) \equiv \int_0^\infty du \int_0^V 4uVe^{-(u^2+V^2)} dV \quad (12)$$

$$F_V(u) = \int_0^\infty dV \int_0^u 4uVe^{-(u^2+V^2)} du \quad (13)$$

But these marginal distributions are simply the cumulative distribution functions (hereinafter, c.d.f.) for u and V , respectively. From equations (A16) and (A15),

$$\left. \begin{aligned} u^2 &= -\ln(R_u) \\ V^2 &= -\ln(R_V) \end{aligned} \right\} \quad (14)$$

where R_u and R_V are random numbers between 0 and 1. Equations (14) are then used to determine the initial velocities of each test electron.

Distance to collisions. - The distance to collision must be obtained at the start of each new electron trajectory (i.e., on emission from emitter or after a collision).

Equation (2) can also be interpreted as the probability that an electron will suffer a collision in a distance $\ell \leq \ell_c$. This, however, is just the definition of the c.d.f. $F(\ell_c)$ (see appendix A). Hence, from equation (A16) can be obtained a relation between the random numbers R_ℓ and the distribution of path length to collision:

$$R_\ell = 1 - e^{-\alpha\ell_c} \quad (15)$$

where

$$\begin{aligned} \ell_c &= -\left(\frac{1}{\alpha}\right) \ln(1 - R_\ell) \\ &= -\left(\frac{1}{\alpha}\right) \ln(R_\ell) \end{aligned} \quad (16)$$

Scattering angle. - If a collision takes place, then the scattering angle θ must be

determined. From the p.d.f. (eq. (1)), the c.d.f. $F(\theta)$ can immediately be obtained (compare eq. (A3) in appendix A):

$$F(\theta) = \frac{1 - \cos \theta}{2} \quad (17)$$

But in this case the c.d.f. can take on the values $-1 \leq F(\theta) \leq 1$ (forward and backward scattering). Hence, in order to choose randomly from this range (see eq. (A16)), let

$$\cos \theta = 1 - 2R_\theta \quad (18)$$

where once again $0 \leq R_\theta \leq 1$. Equation (18) is the final result since only $\cos^2 \theta$ (and $\sin^2 \theta = 1 - \cos^2 \theta$) is of interest in the actual computations.

Charge density. - The data points y_i are selected by the curve-fitting subroutine (see appendix B where y_i corresponds to the arguments x_α). The contribution of the k^{th} test electron (unit of flux) of velocity $u_k(y)$ to the charge density at each y_i is

$$n_k(y_i) = \frac{1}{\sqrt{\pi} u_k(y_i)} \quad (19)$$

where

$$u(y) = \sqrt{u_0^2 + \varphi(y) - \varphi(y_0)} \quad (20)$$

y_0 is the position of the last "event" (collision or emission), and u_0 is the initial velocity immediately after the last event (i. e. , at the beginning of a new trajectory).

The tallied density at a data point y_i for a total of N_0 histories is then

$$n(y_i) = \frac{1}{\sqrt{\pi} N_0} \sum_k \frac{1}{u_k(y_i)} \quad (21)$$

where the sum over k may be greater than, equal to, or less than N_0 because of collisions and turning points in the potential field.

Current to collector. - The ratio of current density to the collector J to the emitted current density J_0 for each iteration is computed from the relation

$$\frac{J}{J_o} = \frac{N_c}{N_o} \quad (22)$$

where N_c is the number of test electrons reaching the collector.

Monoenergetic Emission

The solution for monoenergetic emission is exactly the same as for thermionic emission with two exceptions. First, instead of choosing from an initial distribution of velocities the initial conditions are, for every electron, $u = 1$ and $V = 0$, and second, the density for N_o histories becomes (cf. eq. (14))

$$n(y_i) = \frac{1}{N_o} \sum_k \frac{1}{u_k(y_i)} \quad (23)$$

COMPUTATIONAL METHODS

The original program was based on the assumption that Monte Carlo computations would be limited to only a few collisions because of the requirement of reasonable computer execution times. Hence, this program was optimized for $L/\lambda < 1$. The results proved this assumption overly pessimistic, but the program was not revised for the present report.

Evaluation of Potential and Potential Minimum

After a curve fit of the density is obtained (subroutine CHEBY, appendix B), the density distribution is given by a power series in y :

$$\begin{aligned} n(y) &= a_o + a_1 y + a_2 y^2 + \dots + a_n y^n \\ &= \sum_{j=0}^k a_j y^j \end{aligned} \quad (24)$$

where k is the degree of the fit.

The potential is obtained by substituting equation (24) in Poisson's equation (eq. (6)) and integrating $n(y)$ term by term:

$$\varphi(y) = c_0 + cy + C \sum_{j=0}^k \frac{a_j}{(j+1)(j+2)} y^{j+2} \quad (25)$$

But since

$$\varphi(0) = 0$$

equation (25) can be written

$$\varphi(y) = \sum_{j=1}^{k+2} c_j y^j \quad (26)$$

$$\left. \begin{aligned} c_j &= \frac{a_j - 2}{j(j-1)} & i \geq 2 \\ c_1 &= \varphi(1) - \sum_{j=2}^{k+2} c_j \end{aligned} \right\} \quad (27)$$

After the a_j have been determined (subroutine CHEBY), the c_j are computed in subroutine COEF(2).

Originally, equation (26) was employed (with k usually equal to 10) each time $\varphi(y)$ was evaluated, but this proved too time consuming. For this reason it was decided to tabulate $\varphi(y)$ at the beginning of each iteration and use the tabulated values whenever possible. The interelectrode space was subdivided into 1024 regions, and the 1025 values of $\varphi(y)$ were tabulated in subroutine MINPHI. At the same time, φ was tested at each evaluation for the minimum value. Hence, the location of the potential minimum was ascertained within $\pm 1/2048$ of the interelectrode separation. In addition, φ was tabulated at data points y_i where the density was to be tallied. The results of tabulating the potential was an eight-fold (and greater) decrease of execution time.

Choosing from the Distribution $e^{-x} dx$

It is pointed out in appendix A that choosing random values X_k from the distribution whose p.d.f. is $e^{-x} dx$ is equivalent to choosing random numbers R_k from the uniform distribution (eq. (A7)) and using equation (A15):

$$X_k = -\ln(R_k) \quad (28)$$

In the present problem, it is possible to identify the random variables u^2 and v^2 with X , and ℓ_c with $(1/\alpha)X$ (eqs. (14) and (16), respectively). The random numbers R_k are obtained from a pseudo-random-number generator of the congruence-method type (ref. 5). This random generator is part of the computer library here at Lewis Research Center.

Although the desired random variable can be obtained directly from equation (28), it was decided to tabulate the X_k instead. A table (1025 entries) was constructed of X_k (subroutine CUMVEL) at the beginning of the program. The table look-up is five times as fast as employing equation (28) each time.

Location of Collision

If a distance to collision ℓ_c is given, the location of the collision y_c is obtained by solving

$$\ell_c = \int_{y_0}^{y_c} \sqrt{1 + \frac{v^2}{u_0^2 + \phi(y') - \phi(y_0)}} dy' \quad (29)$$

Two methods were used to minimize the number of times the integrand, and specifically $\phi(y)$, need be evaluated. First, Simpson's rule was used in a search routine to allow the use of the tabulated values of $\phi(y)$ (see Evaluation of Potential and Potential Minimum section, p. 10), and then the step size (in the use of Simpson's rule) was made to depend on the ratio v^2/u^2 .

The procedure employed for obtaining a reasonable step size can be best explained by an example. Assume that y_c falls between any two points y_0 and y_f . For a straightforward application of Simpson's rule, three values are needed of the integrand in equation (29) at three equidistant values of y : y_1, y_2, y_3 . Initially $y_1 = y_0$. The $\phi(y)$ has already been tabulated at 1025 values of y given by

$$y_m = \frac{m}{1024} \quad m = 0, 1, 2, \dots, 1024 \quad (30)$$

Consequently, y_o and y_f will always be selected equal to tabulated values of y_{m_o} and y_{m_f} . Hence, the first estimate of step size Δ in units of m is given by

$$\Delta = \left[\frac{m_f - m_o}{4} \right] \quad (31)$$

where $[]$ refers to the integral value. A second estimate of step size (obtained as a result of trial and error computations) is given by

$$\Delta' = 2^{4-M}$$

where

$$M = \left[\log_{10}(V^2/u^2) \right]$$

Then, the step size is taken as the minimum of the two estimates.

If the value of Δ from equation (31) is zero (i.e., distance to collision is less than four steps), then Δ is set equal to

$$\Delta = \left[\frac{m_f - m_o}{2} \right]$$

If this should be zero, then the collision location y_c is arbitrarily set equal to y_{m_f} .

CONVERGENCE AND STANDARD DEVIATION

It was observed, during tests of the program, that convergence (in the statistical sense, p. 4) was obtained in the first few iterations. Since the succeeding iterations are treated as independent trials, the problem arises in a production run of just how to decide when convergence occurs. This was done in the following manner.

Each case (given anode potential) was run for a given number of iterations, for example, 15. At the end of each iteration the sample means $n(y_i)$ and J/J_o (see eqs. (21) to (23)) were stored. Each of these stored values is analogous to an experi-

TABLE I. - EFFECT OF VARIOUS PARAMETERS ON STANDARD DEVIATION AND EXECUTION TIME

Item	Type of emission	Electrode spacing to mean free path ratio, L/λ	Dimensionless collector potential, $\phi(1)$	Current density ratio, J/J_0	Standard deviation, σ_J	Sample size	Number of iterations	Collisions (for one iteration)	Execution time, min
1	Mono-energetic ↓	0.1	0.75	0.961	0.001	5 000	10	483	2.42
2		↓	2.0	.972	.0012	5 000	10	503	2.46
3			2.0	.971	.0019	2 000	5	213	.51
4			4.0	.986	.0005	10 000	10	1 079	5.28
5			4.0	.918	.0015	2 000	10	1 257	2.48
6	Thermionic ↓	1.0	4.0	.839	.0015	1 000	10	1 483	2.09
7		5.0	12.0	.358	.009	1 000	15	8 475	17.7
8		5.0	32.0	.672	.003	1 000	18	16 367	37.65
9		.1	10.2	.942	.0016	1 000	10	147	1.49
10		.1	10.2	.942	.0008	10 000	10	1 198	14.18

mental data point. Carrying the analogy further, at the end of 15 runs (iterations) there were sets of 15 data points for each of the sample means. If this were an experiment, it would be expected that each set of 15 data points would have a certain amount of "scatter" due to random error. In the present situation, however, the iterations before convergence will produce data points with a nonrandom error. The problem then becomes one of simply eliminating the iterations that introduce a nonrandom error. This was accomplished by obtaining the sample mean and standard deviation (see appendix A) of each set of 15 data points. Then from each set only those points were retained that were within three standard deviations of the sample mean. The final values of sample means and standard deviation (given in table I) were obtained from the remaining data points. In all cases, the number of iterations treated as independent trials was of the order of ten.

RESULTS

Thermionic Emission

The effect of mean free path on the current-voltage characteristic is shown in figure 3. The solid line, $L/\lambda = 0$, represents the collisionless solution of Langmuir (ref. 3). The Monte Carlo calculations indicated along this curve were undertaken as a check on the computer program. These particular results were obtained with 5000 histories per iteration and ten iterations. The execution time for each point on the curve varied between 2.5 and 4.0 minutes.

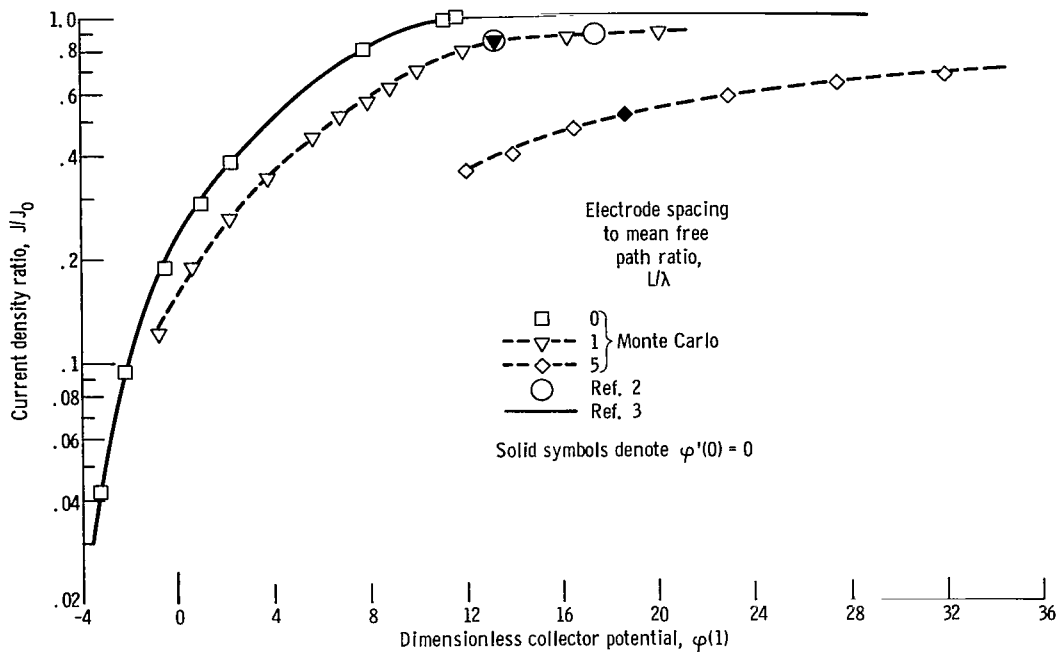


Figure 3. - Effect of mean free path on current-voltage characteristics for thermionic emission. Dimensionless constant $C = 50$.

The two solid data points on the curves for $L/\lambda = 1$ and 5 represent the conditions where the slope of the potential is zero at the emitter. The O's on the curve $L/\lambda = 1$ indicate the results of an independent solution of Boltzmann's transport equation for this problem (ref. 2).

The curve for $L/\lambda = 5$ was not extended to lower $\phi(1)$ because of a loss in precision in the curve-fitting routine program (appendix B) used to fit the density distribution. A more flexible routine is being developed.

The effect of potential on the electron density distribution is shown in figure 4. From the emitter out to about one mean free path, the density of the higher energy electrons is less than that of the lower energy electrons as would be expected under conditions of no collisions. The actual decrease in the magnitude of the density at the emitter surface, however, indicates that in the higher potential case more of the backscattered electrons are being turned about by the potential field before reaching the emitter. This can be best understood by considering the effect of an accelerating potential field on the cone of capture at the emitter for backward scattering (see fig. 5). This cone of capture may be defined by a polar angle θ^* . It will suffice to consider a first collision whereby the electron has initial energy of $u_0^2 + V_0^2$ and the collision occurs at x_c . The magnitude of the x-component of velocity after scatter becomes

$$u^2 = [u_0^2 + V_0^2 + \phi(x_c)] \cos^2 \theta \quad (32)$$

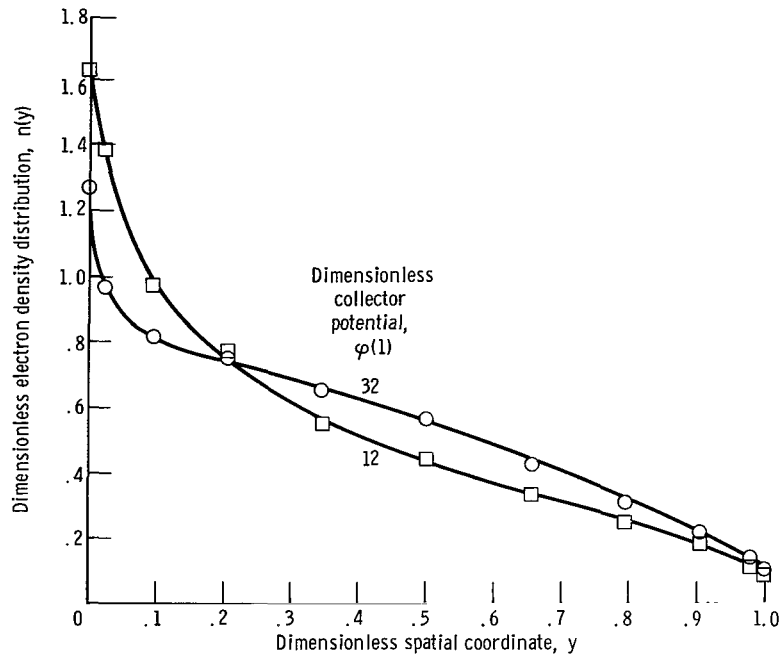


Figure 4. - Effect of anode potential on electron density distribution for thermionic emission. Dimensionless constant $C = 50$; electrode spacing to mean free path ratio $L/\lambda = 5$.

If the electron is to reach the emitter against the monotonic potential field $\varphi(x) \geq 0$, then u^2 must satisfy the condition

$$u^2 \geq \varphi(x_c) \quad (33)$$

When equation (33) is substituted into equation (32), θ^* is defined by

$$\cos^2 \theta^* = \frac{\varphi(x_c)}{u_o^2 + v_o^2 + \varphi(x_c)}$$

or

$$\cos^2 \theta^* = \frac{1}{1 + \frac{u_o^2 + v_o^2}{\varphi(x_c)}} \quad (34)$$

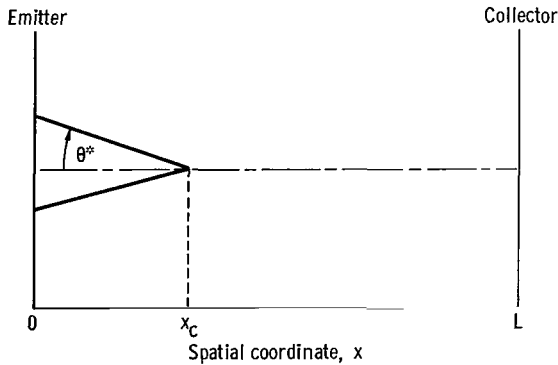


Figure 5. - Cone of capture at emitter.

Equation (34) shows that an increase in potential $\varphi(x_c)$ increases $\cos^2 \theta^*$ and reduces θ^* .

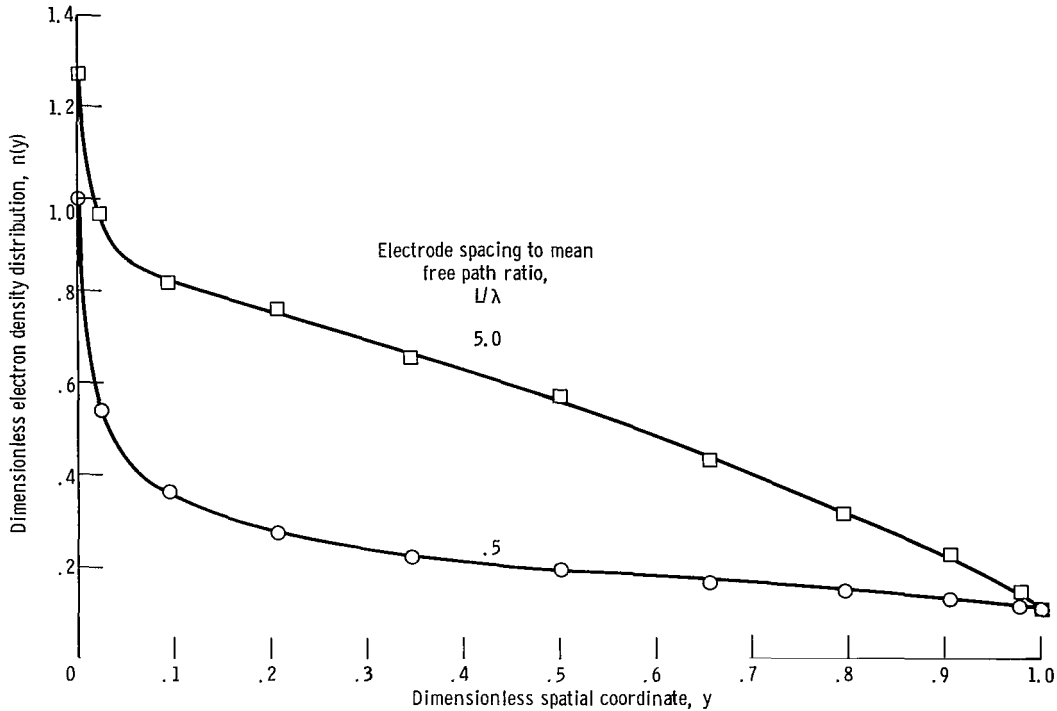


Figure 6. - Effect of mean free path on electron density distribution for thermionic emission. Dimensionless constant $C = 50$; dimensionless collector potential $\varphi(1) = 32$.

Thus, the higher the potential field, the smaller is the cone of capture at the emitter.

This same phenomenon accounts for the crossover in the curves of figure 4 away from the emitter. Since fewer of the backscattered electrons in the higher electric field case reach the emitter, this implies that more are turned about by the field. The presence of turning points in the electron trajectories affects the charge density in two ways. Since the u -component of velocity is zero at a turning point, the contribution to the charge density there is exceptionally high; in addition, the path length of an electron in the neighborhood of a turning point is much greater than the distance traveled normal to an electrode surface, these electrons suffer more collisions, and, hence, contribute more strongly to the charge density. This latter point is vividly illustrated by comparing the typical number of collisions per iteration for the two cases of figure 4 (items 7 and 8, table I, p. 14). In the low potential case ($\varphi(1) = 12$) over 8000 collisions were observed in one iteration, while for the high potential case ($\varphi(1) = 32$) over 16 000 collisions were observed. The increase in number of collisions accounts for the crossover in the two curves of figure 4 and the higher density for $y > 0.2$ in the case $\varphi(1) = 32$.

The effect of mean free path on the density and potential distributions for constant collector potential are shown in figures 6 and 7, respectively. As expected, the effect of collisions is to increase the charge density and, therefore, decrease the potential in the interelectrode space.

Monoenergetic Emission

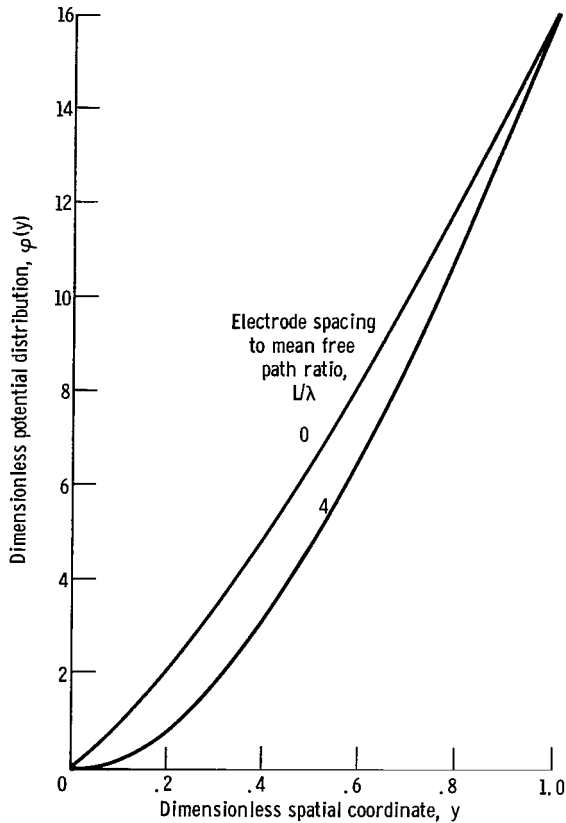


Figure 7. - Effect of mean free path on potential distribution for thermionic emission. Dimensionless constant $C = 50$.

The corresponding diode characteristics for monoenergetic emission are shown in figures 8 to 11. The author has, at present, no hypothesis regarding the inflections observed in the current-voltage characteristics (fig. 8) for $L/\lambda = 0.5$ and 1.0 . The points calculated are reproducible, and each point, as plotted, spans at least plus or minus two standard deviations about the mean J/J_0 . The solid lines represent independent solutions of the Boltzmann equation for this problem in the limit of one collision (ref. 14).

Another noteworthy feature of the monoenergetic emission characteristics is the buildup of charge density in the interelectrode region as the potential is decreased (fig. 9). This increase in charge density is considerably enhanced by the appearance of a potential minimum (upper curve in fig. 9). The potential minimum causes more turning points to occur in the trajectories of the scattered

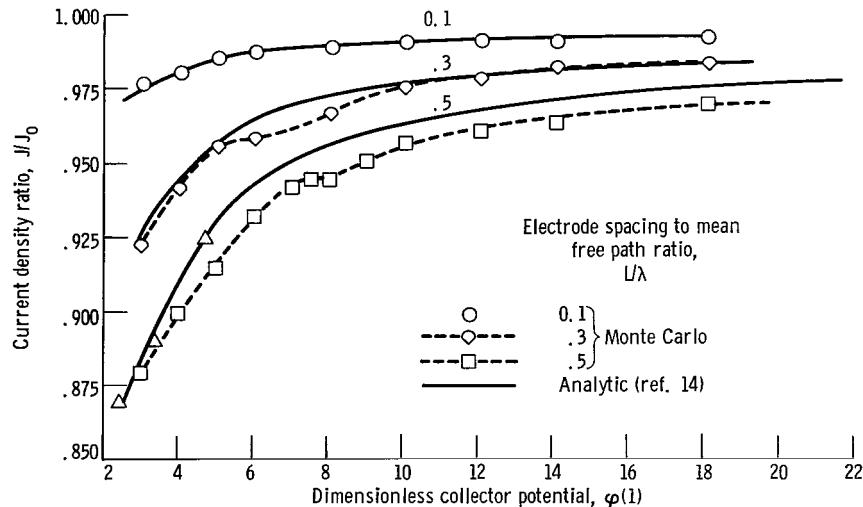


Figure 8. - Effect of mean free path on current-voltage characteristics for monoenergetic emission. Dimensionless constant $C = 10$.

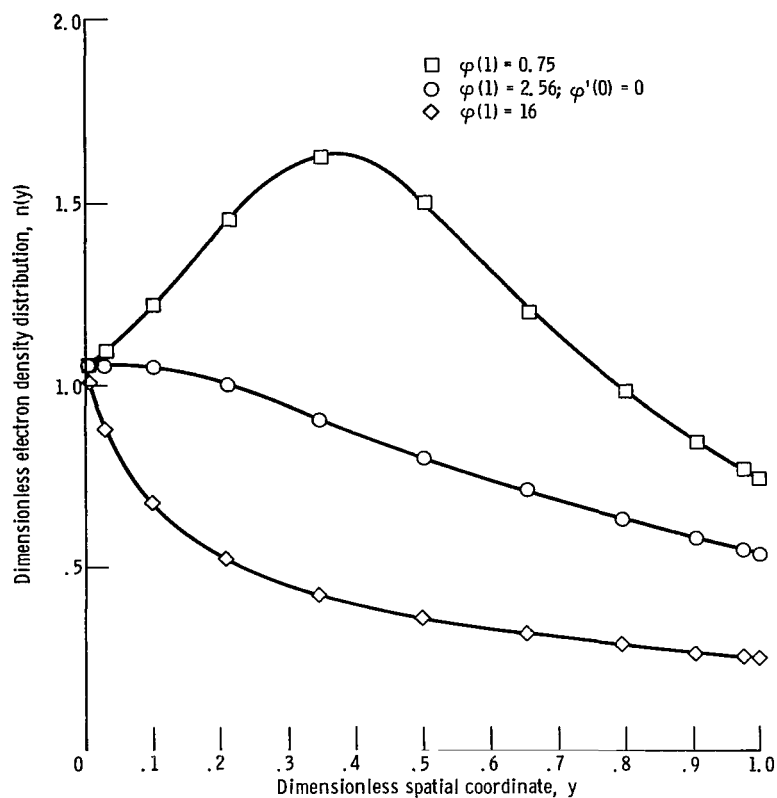


Figure 9. - Effect of anode potential on electron density distribution for electron beam. Dimensionless constant $C = 10/\sqrt{\pi}$; electrode spacing to mean free path ratio $L/\lambda = 0.1$.

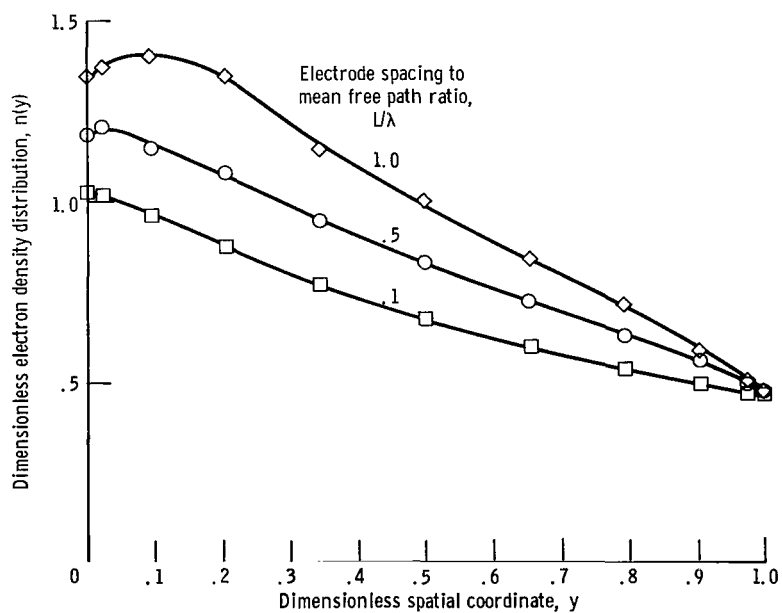


Figure 10. - Effect of mean free path on electron density distribution for electron beam. Dimensionless constant $C = 10/\sqrt{\pi}$; dimensionless collector potential $\varphi(1) = 4$.

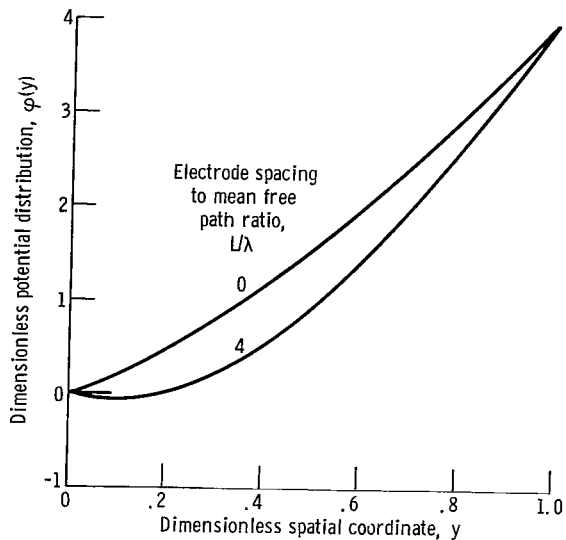


Figure 11. - Effect of mean free path on potential distribution for monoenergetic emission. Dimensionless constant $C = 10/\sqrt{\pi}$.

electrons. Since the u -component of velocity becomes zero at a turning point, the contribution to the charge density of electrons undergoing reflections in the potential field is exceptionally high.

DISCUSSION OF RESULTS

The agreement of the solution obtained by the method proposed in this report and the independent results of Sockol (ref. 2 and fig. 3, p. 15) and Goldstein and Goldstein (ref. 14 and fig. 8) is very gratifying indeed. Most encouraging, with regard to the extension of this method to other problems, are the statistics presented in table I (p. 14). These statistics

show that the execution times needed to obtain reasonable standard deviations σ_J need not be excessive. In turn, they illustrate the effect of the consistent-field constraint (Poisson's equation) on the number of histories needed for good statistics (tens and hundreds of thousands of histories are generally required in other problems where this constraint is absent). It must be emphasized that the execution times illustrated in table I are not the minimum attainable, since no attempt has yet been made to incorporate any of the variance-reducing techniques discussed in the literature (ref. 15).

The execution times in the problems treated herein could most directly be decreased by a more extensive use of tabulated values (eliminating the Gaussian quadratures - hence, obviating completely the need to evaluate $\phi(y)$ during an iteration) and by optimizing the number of tabulations needed (one may not need 1025 tabular values). In addition, for larger values of L/λ , it would be more appropriate to step along each trajectory from the emitter instead of first ascertaining if a collision has occurred in the interelectrode space as is done in the present case.

CONCLUDING REMARKS

A general method for the calculation of transport properties in a low-density ionized gas has been presented. This method has been applied to two cases of electron transport in a perfect Lorentzian gas. Excellent agreement has been demonstrated by two other independent investigations.

Although the particular applications of the method presented herein employ a hard-

sphere collision model, the great advantage in the Monte Carlo method lies in its inherent ability to provide similar solutions for any given collision model, theoretical or experimental. This includes inelastic, charge exchange, and ionizing collisions. This method is limited, however, to those cases where avalanche ionization does not occur; even in this latter case, however, the Monte Carlo method should be capable of providing the source intensities for the collision term in the Boltzmann equation for arbitrary cross sections, and, therefore, allow a numerical solution of the same.

This method should also be of value in the solution of plasma sheath problems, which are, in reality, just generalizations of the diode problem with different boundary conditions at the emitter and/or collector.

Lewis Research Center,
National Aeronautics and Space Administration,
Cleveland, Ohio, May 14, 1965.

APPENDIX A

RANDOM VARIABLES

In this section there is interest only in continuous probabilities for which there exists a continuous function $f(x)$, called the probability distribution function (hereinafter p. d. f.), such that

$$P[a \leq X \leq b] = \int_a^b f(x)dx$$

$$P[-\infty < X < \infty] = \int_{-\infty}^{+\infty} f(x)dx = 1 \quad (A1)$$

where

$$f(x) \geq 0 \quad -\infty < X < \infty$$

To speak of a "random variable" X (instead of x) is really to define a mathematical point of view. This unambiguous point of view maintains no interest in the exact value of X but instead is only interested in inquiring about the probability of finding X in a certain region (of x -space).

For example, the case is considered where the probability density function is the nondimensionalized Maxwellian distribution of the x -component of flux (eq. (11) integrated over V):

$$\begin{aligned} f(u)du &= 2ue^{-u^2} du & u \geq 0 \\ &= 0 & u < 0 \end{aligned} \quad (A2)$$

In the present analysis, the concern is not for a knowledge of a particular value of u , but rather to determine just what the probability is that a random variable U lies in the range $u, u + \Delta u$.

In the study of a random variable X the function $F_X(x)$ is of great importance:

$$F_X(x) = P[X \leq x] \equiv \int_{-\infty}^x f(x')dx' \quad (A3)$$

This $F_X(x)$, or simply $F(x)$, is called the cumulative distribution function (hereinafter c.d.f.) of the random variable X . This function shall be used subsequently.

A concept basic to the discussion of random variables is the expectation value $E[]$ of a function of a random variable $g(X)$:

$$E[g(X)] = \int_{-\infty}^{+\infty} g(x)f(x)dx \quad (A4)$$

In particular, the expectation of a random variable itself

$$E[X] = \int_{-\infty}^{+\infty} xf(x)dx \quad (A5)$$

is the familiar mean or average value of X , $-\infty < X < \infty$. Of interest in the text is the expectation of the function $1/U$ of the random variable U distributed as $f(u)$ (eq.(A2)).

$$\begin{aligned} E\left[\frac{1}{U}\right] &= \int_0^{+\infty} \frac{1}{u} 2ue^{-u^2} du \\ &= 2 \int_0^{\infty} e^{-u^2} du \end{aligned}$$

hence,

$$E\left[\frac{1}{U}\right] = \sqrt{\pi} \quad (A6)$$

Choosing from a Distribution

It is first necessary to define what is meant by choosing a sequence of random numbers X_k from a distribution $f(x)$ (or equivalently, choosing X_k distributed as $f(x)$). It is assumed, for the sake of illustration, that the p.d.f. $f(x)$ is nonzero only in the interval $0 \leq x \leq 1$. This interval is then subdivided into 10 equal subintervals. Then, if the sequence of N random numbers X_k is distributed as $f(x)$, a plot of N_i/N against the midpoint of the i^{th} interval (where N_i is the number of X_k 's in the i^{th} interval) should approximate $f(x)$. Of course, the larger the number N , and/or the smaller the subdivision used, the better will be the approximation.

How is a sequence of random numbers, say U_k distributed as $f(u)$ (eq. (A2)), chosen on a digital computer? In practice, this sequence is not obtained; instead, a sequence of random (pseudo-random) numbers R_k is obtained, distributed as the uniform distribution

$$\left. \begin{aligned} p(r) &= 0 & r < 0 \\ &= 1 & 0 \leq r \leq 1 \\ &= 0 & r > 1 \end{aligned} \right\} \quad (A7)$$

Hence the immediate problem then becomes, given a sequence of random numbers R_k distributed as $p(r)$ (eq. (A7)), how to obtain, even indirectly, a sequence of random numbers U_k distributed as $f(u)$ (eq. (A2)).

Consider two random variables X and Y related by the monotonic increasing function

$$Y = h(X) \quad (A8)$$

where X has a known p.d.f. $f(x)$. Then if x and y are corresponding values related by equation (A8),

$$P[Y < y] = P[X < x] \quad (A9)$$

and

$$\left. \begin{aligned} P[Y < y] &= G_Y(y) = \int_{-\infty}^y g(y') dy' \\ P[X < x] &= F_X(x) = \int_{-\infty}^x f(x') dx' \end{aligned} \right\} \quad (A10)$$

or

$$\int_{-\infty}^y g(y') dy' = \int_{-\infty}^x f(x') dx' \quad (A11)$$

The inverse problem can now be considered. If $g(y)$ and $f(x)$ are given, the functional relationship between y and x (eq. (A8)), such that equation (A9) is still valid,

must be determined. This relation can be easily obtained providing both integrals of equation (A11) can be solved in closed form. For example, if the p.d.f.'s $p(r)$ (eq. (A7)) and $f(u)$ (eq. (A2)) are employed,

$$\int_0^R p(r)dr = \int_0^U f(u)du \quad (A12)$$

$$\int_0^R 1 dr = \int_0^U 2ue^{-u^2} du \quad (A13)$$

$$R = -e^{-U^2} + 1 \quad (A14)$$

or

$$U^2 = -\ln(1 - R)$$

but since R is a random number between 0 and 1, $1 - R$ is also a random number between 0 and 1; hence,

$$U^2 = -\ln R \quad (A15)$$

is the required functional relationship between U and R . Therefore, only a sequence of random numbers R_k from the uniform distribution $p(r)$ (eq. (A7)) need be obtained, and then equation (A15) can be used to obtain a sequence of random numbers U_k distributed as $f(u)$ (eq. (A2)).

Generalizing the previous procedure to obtain a sequence of random numbers X_k distributed as $f(x)$, and given a sequence of random numbers R_k from the uniform distribution (eq. (A7)), it is only necessary to solve the equation

$$R_k = F(X_k) \quad (A16)$$

where $F(x)$ is the c.d.f. (eq. (A3)) of X .

This method becomes unwieldy, however, whenever $F(x)$ cannot be expressed in closed form as in the preceding example. There do exist techniques for choosing from distributions in this case (e.g., the rejection method, ref. 14), but they need not be discussed here.

Another important aspect of random sampling from a given distribution is the result of summing the random numbers, or a function of the random numbers, obtained. For

instance, if a sequence of random numbers X_k is chosen and distributed as $f(x)$, there is obtained upon summing

$$\lim_{N \rightarrow \infty} \frac{1}{N} \sum_{k=1}^N X_k = E[X] \equiv \int_{-\infty}^{+\infty} xf(x) dx \quad (A17)$$

This is readily extended to

$$\lim_{N \rightarrow \infty} \frac{1}{N} \sum_{k=1}^N g(X_k) = E[g(X_k)] \equiv \int_{-\infty}^{+\infty} g(x)f(x)dx \quad (A18)$$

For a particular case of interest in the text

$$\lim_{N \rightarrow \infty} \frac{1}{N} \sum_{k=1}^N \frac{1}{U_k} = E\left[\frac{1}{U_k}\right] = \sqrt{\pi} \quad (A19)$$

from equation (A6), where U is distributed as $f(u)$ (eq. (A2)). A sample mean is defined as

$$\bar{g}_N = \frac{1}{N} \sum_{k=1}^N g(X_k) \quad (A20)$$

for finite N .

Standard Deviation

If the random variable X is distributed as $f(x)$ and $g(x)$ is an integrable function of x , then

$$E[g] \equiv \int_{-\infty}^{+\infty} g(x)f(x)dx$$

$$E[g^2] \equiv \int_{-\infty}^{+\infty} g(x)^2 f(x)dx$$

and the standard deviation of $g(x)$ is defined as

$$\hat{\sigma}_g^2 \equiv E[(g - E[g])^2] \equiv \int_{-\infty}^{+\infty} \{g(x) - E[g]\}^2 f(x) dx = E[g^2] - E[g]^2 \quad (A21)$$

It is noted that this definition of $\hat{\sigma}_g$ is based on a knowledge of the p.d.f. of X . It can be shown that an unbiased estimate of $\hat{\sigma}_g$ can be obtained (ref. 10, p. 370, exercise 4.6) from a random sequence $\{g(X_k)\}$ by the formula

$$\sigma_g^2 = \frac{1}{N-1} \sum_{k=1}^N [g(X_k) - \bar{g}]^2 \quad (A22)$$

Equation (A22) represents the computation performed in the text to obtain σ_J (see table I, p. 14).

Central Limit Theorem

This theorem (ref. 4, p. 362) is central to all Monte Carlo problems. It is based on the fact that regardless of the distribution of X , the sample means \bar{g} (eq. (A20)) are distributed approximately as a normal distribution.

The central limit theorem can then be stated as

$$\lim_{N \rightarrow \infty} P \left[E(g) + \frac{\alpha \sigma_g}{\sqrt{N}} < \bar{g}_N < E(g) + \frac{\beta \sigma_g}{\sqrt{N}} \right] = \frac{1}{\sqrt{2\pi}} \int_{\alpha}^{\beta} e^{-t^2/2} dt \quad (A23)$$

For $\alpha = -1$ and $\beta = 1$, this theorem shows that the probability of the sample mean lying within $\pm \sigma_g / \sqrt{N}$ of the true value is approximately 0.95.

APPENDIX B

COMPUTER PROGRAMS

by Harold E. Renkel

Curve Fitting Program

Subroutine CHEBY listing is a program for determining a finite approximation $f_N(x)$ in the least squares sense to data y_α obtained at the arguments x_α where

$$f_N(x) = \sum_{k=0}^N a_k x^k \quad (B1)$$

In the present problem the advantage is being able to choose the arguments before taking the data. This permits the application of Chebyshev polynomials as described by Lanczos (ref. 16). This method is both very powerful and very efficient. The coefficients a_k in equation (B1) are obtained without the need of inverting a matrix as is usual in the ordinary method of least squares curve fitting.

The arguments x_α are found from

$$x_\alpha = \frac{1}{2} [\cos \theta_\alpha + 1] \quad (B2)$$

where

$$\theta_\alpha = \alpha T/N$$

Then an expansion for $f_N(x)$ in terms of the shifted Chebyshev polynomial (ref. 16) $T_k(x)$ is obtained:

$$f_N(x) = \frac{1}{2} b_0 + \sum_{k=1}^N b_k T_k(x) \quad (B3)$$

The coefficients b_k are obtained from

$$b_k = \frac{1}{2} y_0 + \sum_{\alpha=1}^{N-1} y_\alpha T_k(x_\alpha) + \frac{1}{2} y_N T_k(x_N) \quad (B4)$$

where

$$T_k(x_\alpha) \equiv \cos(k\theta_\alpha) = \cos\left(k \frac{\alpha\pi}{N}\right) \quad (B5)$$

and y_α are the data obtained at x_α .

Each Chebyshev polynomial, however, can be expressed as a power series in x with integral coefficients:

$$T_k(x) = \sum_{j=0}^N C_{kj} x^j \quad (B6)$$

where the C_{kj} can be obtained from the following recursion relations:

$$\left. \begin{aligned} T_{k+1}(x) &= 2(2x - 1)T_k(x) - T_{k-1}(x) \\ T_0(x) &= 1 \\ T_1(x) &= -1 + 2x \end{aligned} \right\} \quad (B7)$$

Substituting equation (B6) into equation (B3) yields the coefficients a_k (eq. (B1)):

$$a_k = \frac{1}{2} b_0 C_{0k} + \sum_{j=1}^N b_j C_{jk} \quad (B8)$$

In addition, subroutine CHEBY makes use of the symmetry of the trigonometric functions (eq. (B5)) as discussed in reference 17 to reduce the number of multiplications needed.

Gaussian Quadrature

The use of Monte Carlo techniques and variables based on random numbers for

numerically solving problems often demands that a large sampling of data be analyzed to obtain the necessary accuracy of the solution. Such large samplings may require many minutes and even hours of computing time if time saving methods are not employed. Subroutine QUAD is a Fortran IV program that numerically integrates a function $f(x)$ over the range x_1 to x_0 . It is based on the method of Gaussian quadrature (ref. 18) which states that

$$\int_{x_1}^{x_0} f(x)dx = \sum_{j=1}^n H_j f(a_j) + E_n$$

where the H_j 's are a sequence of weight coefficients and the a_j 's are the associated abscissas that have been determined as the roots of certain orthogonal polynomials. The well-known error term E_n based on the $2n^{\text{th}}$ derivative of $f(x)$ is not considered to be of such magnitude as to affect present calculations and therefore has been omitted from subroutine QUAD. In comparison to other more popular methods of numerical integration such as the trapezoidal formula and Simpson's rule, which require that the integrand be evaluated at many points over the range of integration $[x_1, x_0]$, Gaussian quadrature will produce the same accuracy with comparatively fewer evaluations of the integrand, which results in a considerable savings of computing time especially if the integrand $f(x)$ contains trigonometric functions, logarithms, or square roots.

The subroutine in present form includes the weight coefficients and abscissas for $n = 3$ through 16. To apply subroutine QUAD, the function $f(x)$ to be integrated, the upper and lower limits of the integral x_1 and x_0 , and n the number of points of evaluation must all be specified. The program converts the abscissas from the range $[-1, 1]$ to the range $[x_1, x_0]$ by the algorithm

$$x_j(a_j) = X_1 + \frac{1}{2}(x_0 - x_1)(a_j + 1)$$

evaluates the integrand $f(x)$ and x_j , and calculates the sum of the products $H_j f(a_j)$. The final sum is then multiplied by the correction factor $\frac{1}{2}(x_0 - x_1)$ to compensate for the change in the range of the variable of integration.

When analyzing a function to be integrated by this method one must be careful to note any discontinuities in the range of integration $[x_1, x_0]$. If any should exist, then it becomes necessary to divide the region of integration into smaller intervals, choosing the new limits of integration so that comparatively small regions are established in the neighborhood of the discontinuity. This causes the integrand to be evaluated more often

in the neighborhood and results in a more accurate solution. The total integral for the interval $[x_1, x_0]$ is the usual sum of the integrals of each of the subdivisions.

APPENDIX C

FLOW CHARTS AND PROGRAM LISTINGS

The symbols used in the flow charts (figs. 12 to 16) are as follows:

DELX	size of subdivisions
EN	number of subdivisions
FPATH	distance to collision
IC	location number corresponding to XC
IFF	location number of bound to region containing XC
IMIN	location number corresponding to XMIN
IO	location number corresponding to XO
ITP	location number corresponding to XTP
KI	number of iterations
N	number of histories per iteration
PHIMIN	magnitude of potential minimum
S	path length along trajectory from XO to XTP or XC
TPHIX(I)	tabulated values of $\varphi(y)$
USQ	u^2
USQO	u_o^2
VSQ	v^2
XC	location of collision
XMIN	location of potential minimum
XO	location of scatter
XTP	location of turning point

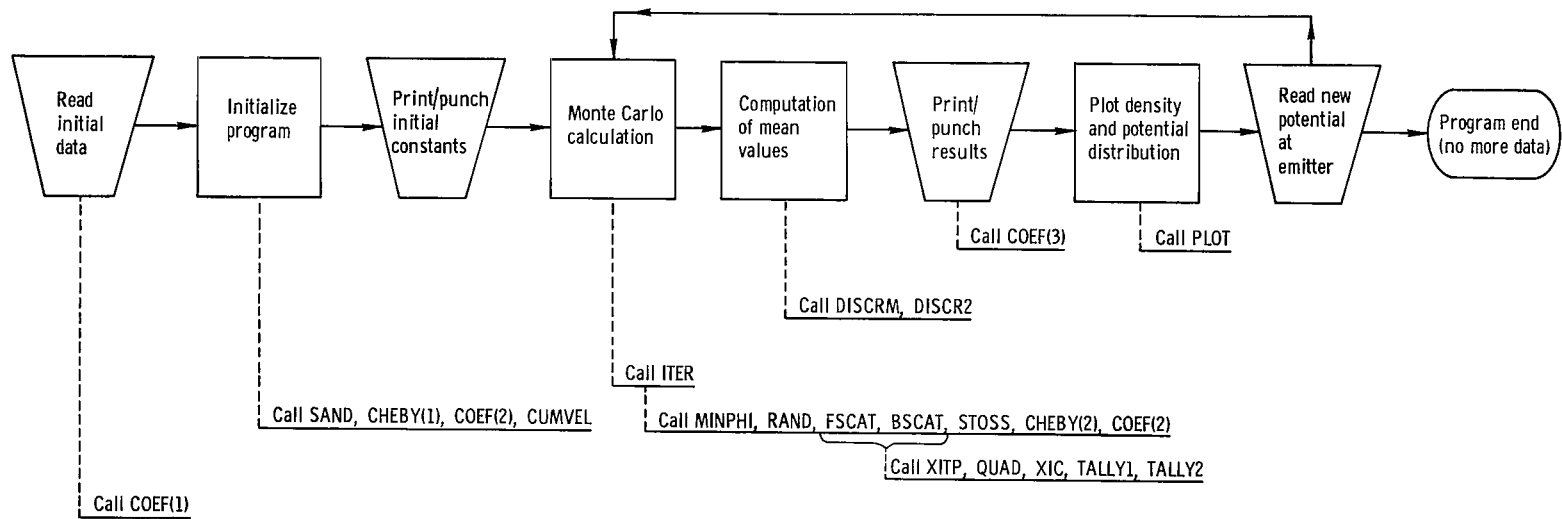


Figure 12. - System and MAIN program flow chart.

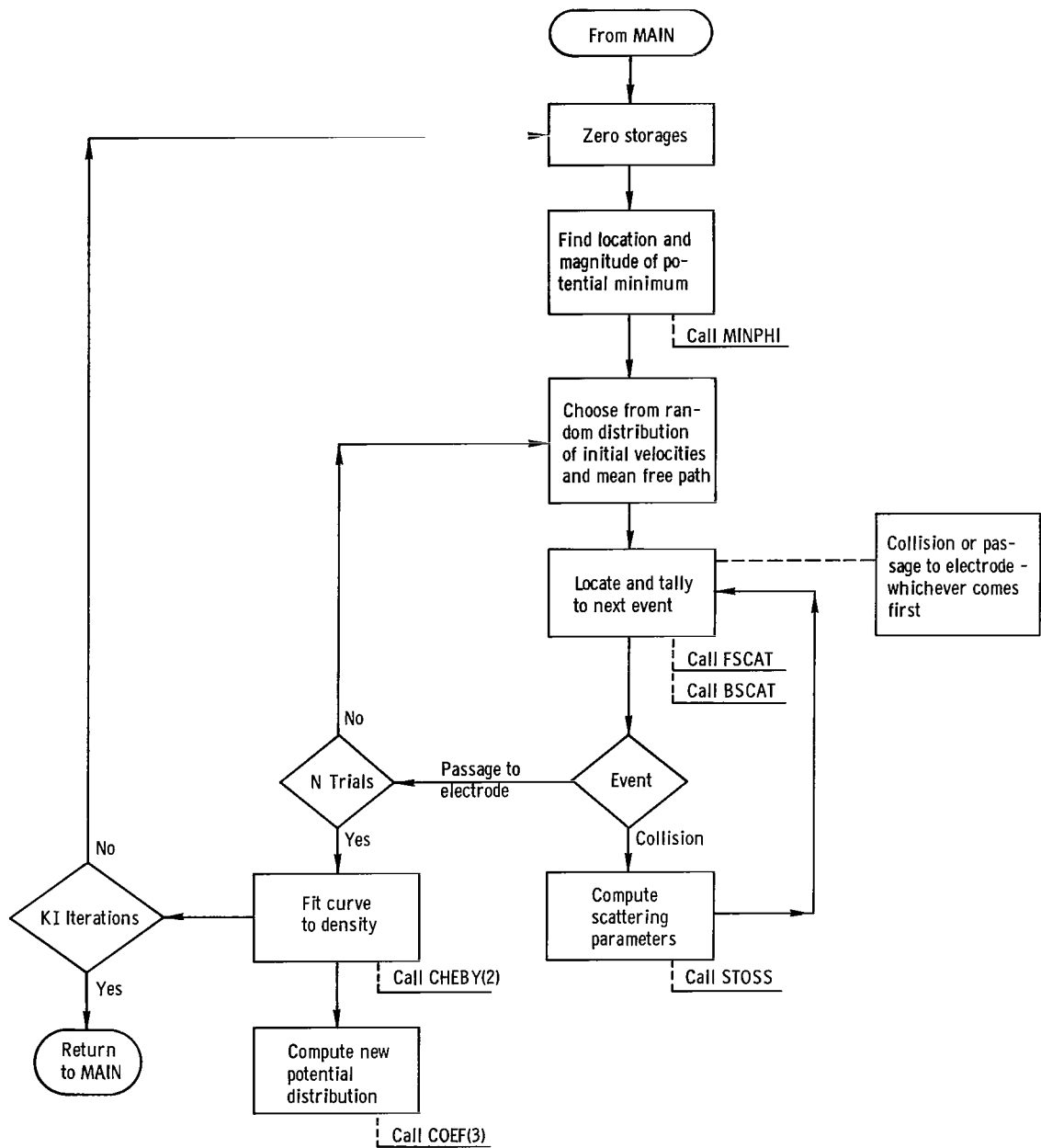


Figure 13. - Subroutine ITER flow chart.

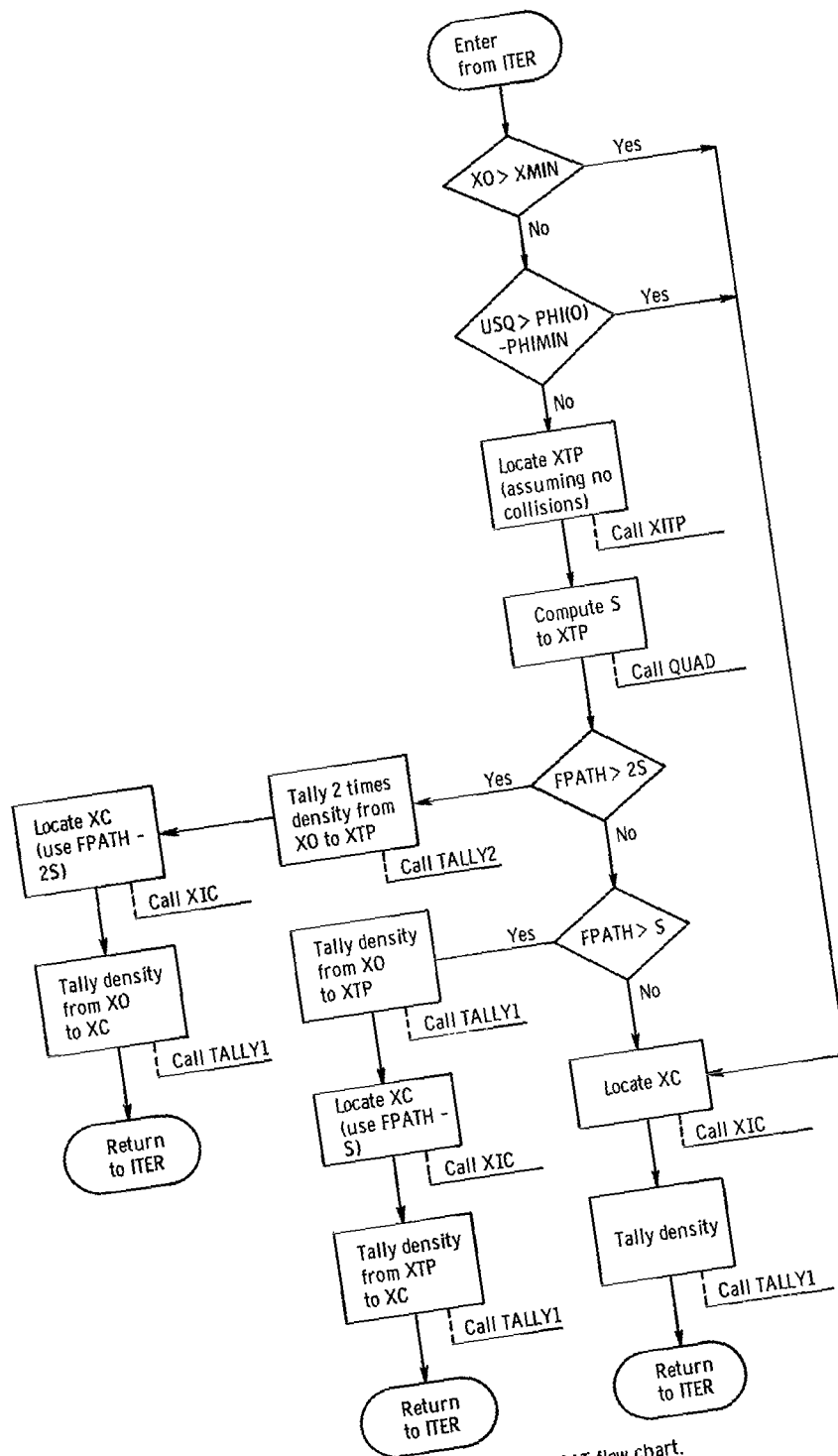


Figure 14. - Subroutine FSCAT flow chart.

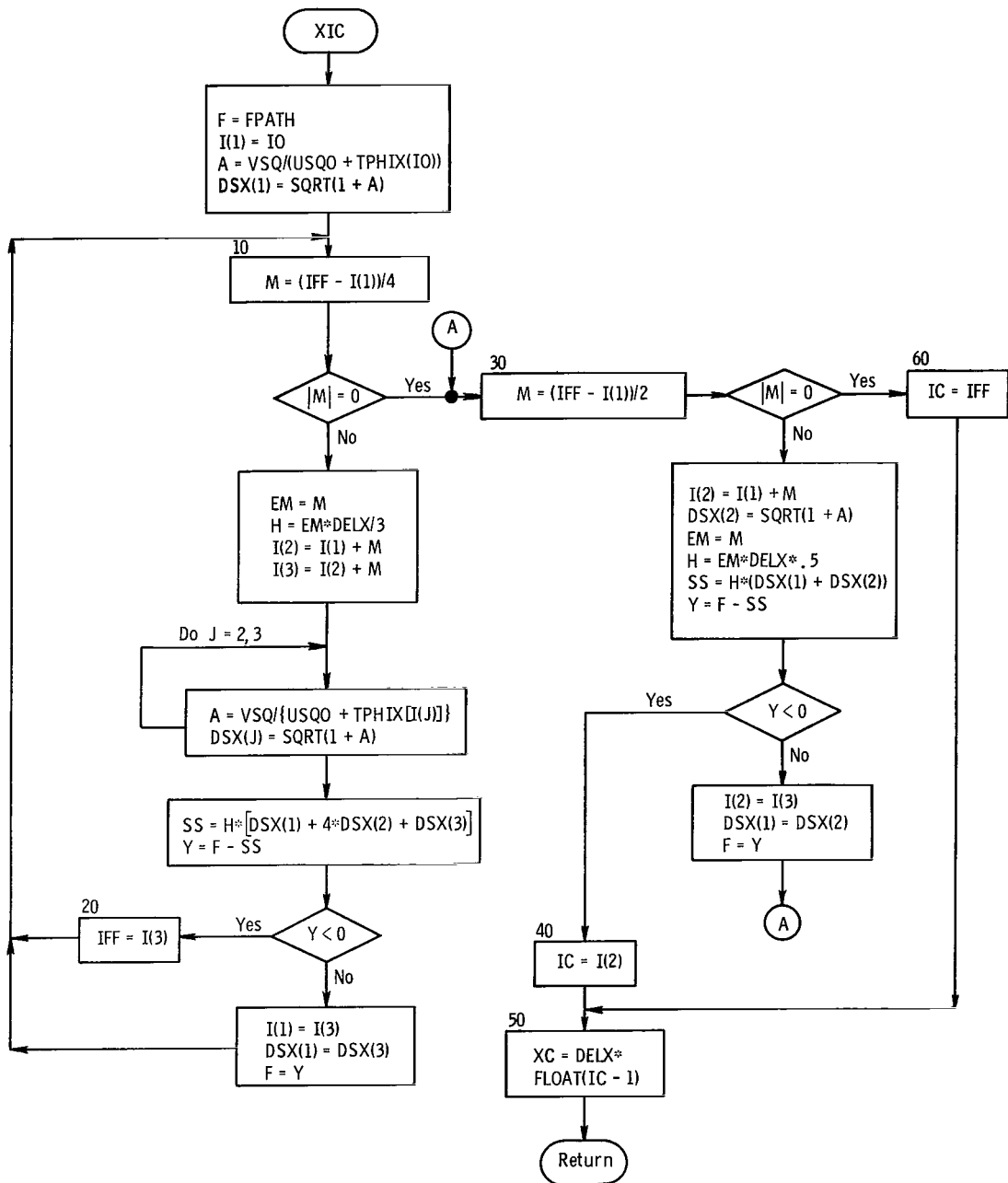


Figure 15. - Subroutine XIC flow chart.

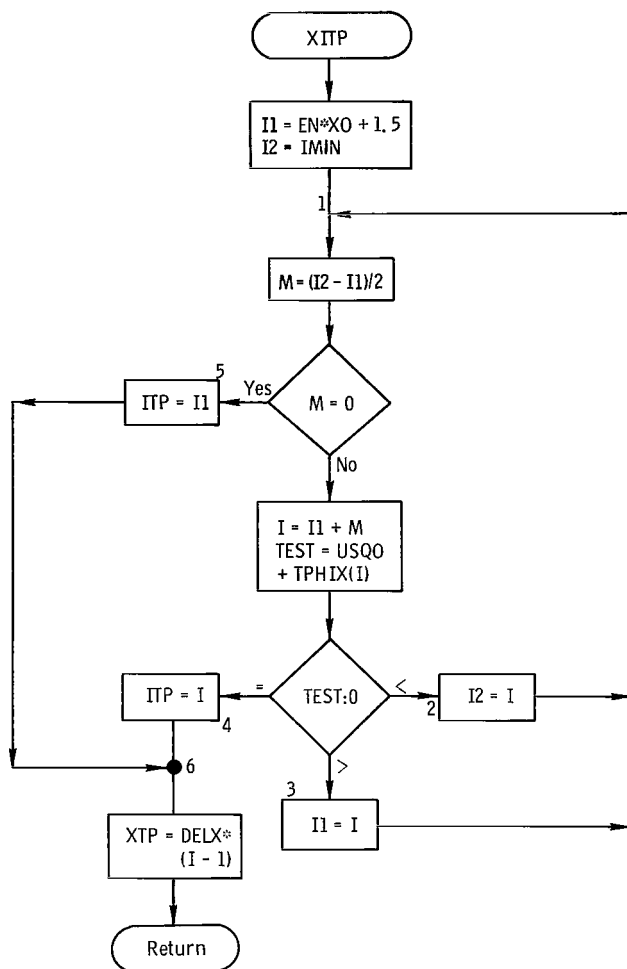


Figure 16. - Subroutine XITP flow chart.

A listing of the **FORTRAN IV** programs used to calculate the transport properties in a low ionized gas follows.

\$IBFTC MAIN	DEBUG,DECK	1	00031
	COMMON/BITER/NO,KI	1	00040
	COMMON/BSTOSS/WSQ,VSQ,COSN,ALPHA	1	00050
	COMMON/8PHI/NPHI,APHI(20),NDPHI,ADPHI(20),NDEN	1	00060
	COMMON/8MAIN/ CONST,VOLT(20),CURRNT(20)	1	00070
	COMMON/BMIN/XMIN,PHIMIN,IMIN,TPHID(33),TPHIX(1026),A,B,C,DELX,EN	1	075
	COMMON/BCHEB/N1,X(21),Y(21),COEFS(21),ERROR	1	00080
	COMMON/BCHEB2/N2	1	00081
	COMMON/BVEL/VEL(1024)	1	00085
	DIMENSION DATE(2)	1	095
	COMMON KNTR,N(20)		
C	NO = NUMBER OF TRIALS PER ITERATION	1	110
C	N1 = NUMBER OF POINTS WHERE DENSITY IS SAMPLED	1	115
C	KI = NUMBER OF ITERATIONS	1	116
C	ALPHA = RATIO OF MFP TO ELECTRODE SPACING	1	117
C	CONST = CONSTANT PRECEEDING DENSITY IN POISSONS EQUATION	1	118
C		1	119
C	READ IN INITIAL DATA	1	120
	READ(5,1) NO,N1,N2,KI,ALPHA,CONST	1	0130
	1 FORMAT(4I5,2E10.0)	1	140
	CALL COEF(1)	1	150
	READ(5,4) DATE	1	151
	4 FORMAT(2A6)	1	152
C		1	155
C	INITIALIZE PROGRAM	1	160
	CALL SAND(RO)	1	170
	CALL CHEBY(1)	1	180
	CALL COEF(2)	1	190
	DEBUG (COEFS(I),I=1,11)	1	00192
	DEBUG(APHI(I),I=1,13)	1	00192
	CALL CUMVEL	1	00194
C		1	205
C	COMPUTE COLLECTOR VOLTAGE AND CURRENT FOR EACH VALUE OF APHI(2)	1	210
	5 READ(5,2) VOLT(20),ALPHA	1	220
	2 FORMAT(2E5.1)	1	230
	3 CALL TIME1(T1)	1	233
C		1	234
C	COMPUTE MEANS AND PRINT / PUNCH OUT RESULTS	1	235
	WRITE(6,100) VOLT(20),CONST,ALPHA,NO,KI,N1,N2	1	236
100	FORMAT(1H1, 39H ANODE POTENTIAL IS ,F6.2/	1	237
1	1X, 39HCONSTANT IN POISSONS EQUATION, C =,F6.2/	1	238
1	1X,39HDIMENSIONLESS MEAN FREE PATH ALPHA=,1PE10.1/	1	00239
1	1X, 39HTRIALS PER ITERATION, NO =,15 /	1	240
1	1X,39HNUMBER OF ITERATIONS KI =, 12 /	1	00243
1	1X, 39HNUMBERS OF SAMPLE POINTS, N1 =,12 /	1	244
1	1X, 39HNO. OF TERMS IN DENSITY FIT N2 =,12)	1	245
	CALL ITER	1	250
	CALL DISCRM	1	270
	CALL DISCR2(CURRNT,CM,CSTD)	1	00290
	CALL CHEBY(2)	1	292
	CALL COEF(2)	1	293
	CALL COEF(3)	1	295
	CALL TIME1(T2)	1	296
	TIME=(T2-T1)/3600.	1	00297
	WRITE(6,203) KNTR	1	298
203	FORMAT(1H0,28HTOTAL NUMBER OF COLLISIONS =,15/	1	299
	11H0,36HNUMBER OF ENTRIES AT EACH DATA POINT)	1	300
	WRITE(6,204) (N(I),I=1,N1)	1	301
204	FORMAT(1H ,11110)	1	302
	WRITE(6,200) VOLT(20),APHI(2),CM,CSTD,XMIN,PHIMIN,TIME	1	303
200	FORMAT(1H0,17HANODE POTENTIAL =,F15.6,6X,28HPOTENTIAL SLOPE AT EMI	1	304
	1TER =,F10.4/1H ,15HANODE CURRENT =,F15.6,6X,9HSTD.DEV.= ,F15.6/	1	305
	11H0,6HXMIN =,F15.6,6X,8HPHIMIN =,F15.6/1H0,6HTIME =,F6.3,	1	306
	18H MINUTES)	1	307
	ELMFP=1./ALPHA	1	308
	WRITE(6,202) DATE,CONST,ELMFP,VOLT(20),CM,CSTD,APHI(2),NO,KI	1	309
202	FORMAT(1H\$,2A6,F7.0,F6.2,F9.3,F9.4,F10.5,F8.2,I7,I4)	1	310
C		1	340
C	PLOT DENSITY AND POTENTIAL DISTRIBUTION	1	350
	CALL PLOT	1	360
	GO TO 5	1	370
	STOP	1	380
	END	1	390

\$IBFTC ITER	DEBUG,DECK	2 00741
	SUBROUTINE ITER	2 00750
C		2 00755
C	MONTE CARLO CALCULATION OF DENSITY AND ITERATION ON POTENTIAL -	2 00756
C	DISTRIBUTION	2 00757
C		2 00758
	COMMON/BMAIN/ CONST,VOLT(20),CURRNT(20)	2 00760
	COMMON/BITER/NO,KI	2 00770
	COMMON/BNXF/XO,XF,XC,XTP,FPATH,S,NQUAD ,K,II	2 00780
	COMMON/BPHI/NPHI,APHI(20),NDPHI,ADPHI(20),NDDPHI	2 00790
	COMMON/BCHEB/N1,X(21),Y(21),COEFS(21),ERROR	2 00800
	COMMON/BMIN/XMIN,PHIMIN,IMIN,TPHID(33),TPHIX(1026),A,B,C,DELX,EN	2 00810
	COMMON/BNIF/IO,IC,ITP,PHIO,USQO	2 00815
	COMMON/BSTOSS/VSQ,VSQ,COSN,ALPHA	2 00820
	COMMON/BVEL/ VEL(1024)	2 00825
	COMMON/BTALLY/ ICM1,DEN(20,20)	2 00830
	COMMON KNTR,N(11)	2 00834
	DATA SQRTPI/1.77245385/	2 00835
	INTEGER A	2 0836
	EQUIVALENCE(A,KNTR2)	2 0837
	DO 35 K=1,KI	2 00840
	CALL TIME1(T1)	2
	NTHRU = 0.	2 00850
	DO 10 I=1,N1	2 00860
	N(I)=0	2 00865
10	DEN(I,K)= 0.	2 00870
C		2 00875
C	DETERMINATION OF LOCATION AND MAGNITUDE OF POTENTIAL MINIMUM	2 00876
	CALL MINPHI	2 00880
	DEBUG(TPHID(I),I=1,11)	2 00882
	KNTR=0	2 00885
	KNTR2=0	2 0886
	DO 33 II=1,NO	2 00900
	CALL RAND(R)	2 00910
	J = IFIX(1024.*R)+1	2 00920
	USQ = VEL(J)	2 00925
	CALL RAND(R)	2 00930
	J = IFIX(1024.*R) +1	2 00940
	VSQ = VEL(J)	2 00945
	CALL RAND(R)	2 00950
	J = IFIX(1024.*R) +1	2 00960
	FPATH = ALPHA*VEL(J)	2 00965
	XO=0.	2 00980
	ICM1=0	2 00990
	CALL FSCAT	2 01000
20	IF(ICM1.EQ.N1) GO TO 32	2 01010
	IF(ICM1.EQ.0) GO TO 33	2 01020
	CALL STOSS	2 01030
	IF(COSN.LT.0.) GO TO 25	2 01040
	CALL FSCAT	2 01050
	GO TO 20	2 01070
25	CALL BSCAT	2 01080
	GO TO 20	2 01100
32	NTHRU = NTHRU+1	2 01110
33	CONTINUE	2 01120
	DO 34 I=1,N1	2 01130
	DEN(I,K) = DEN(I,K)/(FLOAT(NO)*SQRTPI)	2 01140
34	Y(I)= DEN(I,K)	2 01150
	DEBUG(Y(I),I=1,N1)	2 01152
C		2 01154
C	CURVE FIT OF DENSITY AND COMPUTATION OF PHI(X) AND DPHI(X)	2 01155
	CALL CHEBY(2)	2 01160
C		2 01175
	CALL COEF(2)	2 01176
	VOLT(K)=TPHID(N1)	2 01180
	CURRNT(K) = FLOAT(NTHRU)/FLOAT(NO)	2 01190
	DEBUG(N(I),I=1,11)	2 01192
	DEBUG KNTR	2 01192
	DEBUG VOLT(K), CURRNT(K)	2 01194
	CALL TIME1(T2)	2
	TIME=(T2-T1)/3600.	2
	DEBUG TIME	2
35	CONTINUE	2 01195
	RETURN	2 01200
	END	2 01210

\$IBFTC FSCAT DECK	
SUBROUTINE FSCAT	3 01230
COMMON/BMIN/XMIN,PHIMIN,IMIN,TPHID(33),TPHIX(1026),A,B,C,DELX,EN	3 1240
COMMON/BNXF/XO,XF,XC,XTP,FPATH,S,NQUAD ,K,II	3 01250
COMMON/BSTOSS/USQ,VSQ,COSN,ALPHA	3 01260
COMMON/BNIF/IO,IC,ITP,PHIO,USQO	3 01270
IO=EN*XO+1.5	3 1270
PHIO=TPHIX(IO)	3 01275
USQO=USQ-PHIO	3 01276
IF(XO.GE.XMIN) GO TO 6	3 01280
IF(USQO.GT.-PHIMIN) GO TO 4	3 01290
CALL XITP	3 01300
IF(IO.EQ.ITP) GO TO 10	3 1305
XF=XTP	3 01310
CALL QUADGM	3 01340
DIF (K.EQ.1.AND.II.LE.5) DEBUG XTP,S	3 01352
IF(FPATH.GE. 2.*S) GO TO 3	3 01360
IF(FPATH.GE.S) GO TO 2	3 01370
1 CALL XIC	3 01380
DIF (K.EQ.1.AND.II.LE.5) DEBUG XC	3 01392
CALL TALLY1	3 01400
XO=XC	3 01405
RETURN	3 01410
2 XC=XTP	3 01420
CALL TALLY1	3 01430
FPATH=2.*S-FPATH	3 1460
GO TO 1	3 1470
3 CALL TALLY2	3 01510
FPATH = FPATH-2.*S	3 1514
10 IF(XO.EQ.0.) RETURN	3 01515
XF=0.	3 01520
NQUAD=5	3 01525
CALL QUAD	3 01540
DIF (K.EQ.1.AND.II.LE.5) DEBUG FPATH,S	3 01552
IF(FPATH.LT.S) GO TO 1	3 1560
XC=XF	3 01570
CALL TALLY1	3 01580
RETURN	3 01590
6 SMAXSQ=(1.+VSQ/USQ)*(1.-XO)**2	3 01600
IF(FPATH*FPATH.GE.SMAXSQ) GO TO 5	3 01603
4 NQUAD=3	3 01610
IF(XO.LT..2)NQUAD=5	3 01620
IF(XO.LT..2.AND.USQ.LT..01) NQUAD =9	3 01630
XF=1.	3 01640
CALL QUAD	3 01650
DIF(K.EQ.1.AND.II.LE.5) DEBUG NQUAD,S	3 01652
IF(FPATH.GE.S) GO TO 5	3 01660
9 CALL XIC	3 1675
DIF (K.EQ.1.AND.II.LE.5) DEBUG S,XC	3 01682
CALL TALLY1	3 01690
XO=XC	3 01695
RETURN	3 01700
5 XC=1.	3 01710
CALL TALLY1	3 01720
RETURN	3 01730
END	3 01740

```

$1BFTC BSCAT  DECK
SUBROUTINE BSCAT
COMMON/BMIN/XMIN,PHIMIN,IMIN,TPHID(33),TPHIX(1026),A,B,C,DELX,EN
COMMON/BNIF/IO,IC,ITP,PHIO,USQO
COMMON/BNXF/XO,XF,XC,XTP,FPATH,S,NQUAD ,K,II
COMMON/BSTOSS/USQ,VSQ,COSN,ALPHA
IO=EN*XO+1.5
PHIO=TPHIX(IO)
USQO=USQ-PHIO
IF(XO.LT.XMIN)GO TO 4
IF(USQO.GT.-PHIMIN) GO TO 4
CALL XITP
IF(IO.EQ.ITP) GO TO 10
XF=XTP
CALL QUADGM
DIF (K.EQ.1.AND.II.LE.5) DEBUG XTP,S
IF(FPATH.GE. 2.*S) GO TO 3
IF(FPATH.GE.6) GO TO 2
1 CALL XIC
DIF (K.EQ.1.AND.II.LE.5) DEBUG XC
CALL TALLY1
XO=XC
RETURN
2 XC=XTP
CALL TALLY1
FPATH=2.*S-FPATH
GO TO 1
3 CALL TALLY2
FPATH = FPATH-2.*S
10 SMAXSQ=(1.+VSQ/USQ)*(1.-XO)**2
IF(FPATH*FPATH.GE.SMAXSQ) GO TO 6
XF=1.
NQUAD=5
CALL QUAD
DIF (K.EQ.1.AND.II.LE.5) DEBUG FPATH,S
IF(FPATH.LT.S) GO TO 1
6 XC=1
CALL TALLY1
RETURN
4 NQUAD=5
IF(USQ.LT..01) NQUAD=9
XF=0.
CALL QUAD
IF(FPATH.GE.S) GO TO 5
9 CALL XIC
DIF (K.EQ.1.AND.II.LE.5) DEBUG S,XC
CALL TALLY1
XO=XC
RETURN
5 XC=0.
CALL TALLY1
RETURN
END

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$1BFTC STOSS  DECK
SUBROUTINE STOSS
C
C COMPUTATION OF COLLISION PARAMETERS  FOR ELECTRON-NEUTRAL  SCATTERING
C
COMMON/BSTOSS/USQ,VSQ,COSN,ALPHA
COMMON/BNXF/XO,XF,XC,XTP,FPATH,S,NQUAD ,K,II
COMMON/BVEL/VEL(1024)
COMMON/BNIF/IO,IC,ITP,PHIO,USQO
COMMON/BMIN/XMIN,PHIMIN,IMIN,TPHID(33),TPHIX(1026),A,B,C,DELX,EN
WSQ=USQO+VSQ+TPHIX(IC)
CALL RAND(R)
COSN=1.-2.*R
USQ=WSQ*COSN*COSN
VSQ=WSQ-USQ
CALL RAND(R)
J=IFIX(1024.*R)+1
FPATH=ALPHA*VEL(J)
DIF (K.EQ.1.AND.II.LE.5) DEBUG USQ,VSQ,COSN,FPATH
RETURN
END

```

\$IBFTC TALLY1 DECK	6 02401
SUBROUTINE TALLY1	6 02410
COMMON/BSTOSS/USQ,VSQ,COSN,ALPHA	6 02420
COMMON/BNXF/XO,XF,XC,XTP,FPATH,S,NQUAD ,K,II	6 02430
COMMON/BCHEB/N1,X(21),Y(21),COEFS(21),ERROR	6 02440
COMMON/BTALLY/ ICM1,DEN(20,20)	6 02450
COMMON/BMIN/XMIN,PHIMIN,IMIN,TPHID(33),TPHIX(1026),A,B,C,DELX,EN	6 02460
COMMON/BNIF/IO,IC,ITP,PHIO,USQO	6 02465
COMMON KNTR,N(11)	6 02470
IF(XO.GT.XC) GO TO 7	6 02480
I = ICM1	6 02490
GO TO 10	6 02500
1 DEN(I,K) = DEN(I,K) + 1./SQRT(TEST)	6 02510
DIF (K.EQ.1.AND.II.LE.5) DEBUG DEN(I,K)	6 02512
N(I)=N(I)+1	6 02515
10 I = I+1	6 02520
TEST=USQO+TPHID(I)	6 02525
IF(TEST.LE.0.) GO TO 3	6 02526
IF(X(I).EQ.XC) GO TO 2	6 02530
IF(X(I).LT.XC) GO TO 1	6 02535
GO TO 3	6 02536
2 DEN(I,K) = DEN(I,K) + 1./SQRT(TEST)	6 02540
N(I)=N(I)+1	6 02545
DIF (K.EQ.1.AND.II.LE.5) DEBUG DEN(I,K)	6 02552
ICM1=I	6 02560
RETURN	6 02570
7 I = ICM1+1	6 02580
GO TO 11	6 02585
4 DEN(I,K) = DEN(I,K) + 1./SQRT(TEST)	6 02590
N(I)=N(I)+1	6 02595
DIF (K.EQ.1.AND.II.LE.5) DEBUG DEN(I,K)	6 02602
11 I = I-1	6 02610
TEST=USQO+TPHID(I)	6 02615
IF(TEST.LE.0.) GO TO 6	6 02616
IF(X(I).EQ.XC) GO TO 5	6 02620
IF(X(I).GT.XC) GO TO 4	6 02625
GO TO 6	6 02626
5 DEN(I,K) = DEN(I,K) + 1./SQRT(TEST)	6 02630
N(I)=N(I)+1	6 02635
DIF (K.EQ.1.AND.II.LE.5) DEBUG DEN(I,K)	6 02642
ICM1=I-1	6 02650
RETURN	6 02660
3 ICM1=I-1	6 02670
RETURN	6 02680
6 ICM1=I	6 02690
RETURN	6 02700
END	6 02710

\$IBFTC TALLY2 DECK	7 02721
SUBROUTINE TALLY2	7 02730
COMMON/BTALLY/ ICM1,DEN(20,20)	7 02740
COMMON/BSTOSS/USQ,VSQ,COSN,ALPHA	7 02750
COMMON/BNXF/XO,XF,XC,XTP,FPATH,S,NQUAD ,K,II	7 02760
COMMON/BCHEB/N1,X(21),Y(21),COEFS(21),ERROR	7 02770
COMMON/BMIN/XMIN,PHIMIN,IMIN,TPHID(33),TPHIX(1026),A,B,C,DELX,EN	7 02780
COMMON/BNIF/IO,IC,ITP,PHIO,USQO	7 02785
COMMON KNTR,N(11)	7 02786
IF(XO.GT.XTP) GO TO 2	7 02800
I=ICM1	7 02810
GO TO 3	7 02815
1 DEN(I,K)=DEN(I,K)+2./SQRT(TEST)	7 02820
N(I)=N(I)+1	7 02825
DIF (K.EQ.1.AND.II.LE.5) DEBUG DEN(I,K)	7 02832
3 I=I+1	7 02840
TEST=USQO+TPHID(I)	7 02845
IF(TEST.GT.0..AND.X(I).LT.XTP) GO TO 1	7 02850
RETURN	7 02860
2 I=ICM1+1	7 02870
GO TO 4	7 02875
5 DEN(I,K)=DEN(I,K)+2./SQRT(TEST)	7 02880
N(I)=N(I)+1	7 02885
4 I=I-1	7 02890
TEST=USQO+TPHID(I)	7 02900
IF(TEST.GT.0..AND.X(I).GT.XTP) GO TO 5	7 02910
DIF (K.EQ.1.AND.II.LE.5) DEBUG DEN(I,K)	7 02912
RETURN	7 02920
END	7 02930

\$IBFTC DISCRM DECK	8029051
SUBROUTINE DISCRM	8029060
REAL MEAN1, MEAN2	8029070
COMMON/BITER/NO,K	8 29080
COMMON/BTALLY/ ICM1,DEN(20,20)	8029090
COMMON/BCHEB/N1,X(21),Y(21),COEFS(21),ERROR	8029100
WRITE(6,100)	8029110
100 FORMAT(1HL, 47H MEAN DENSITIES BEFORE AND AFTER DISCRIMINATION /1H	8029120
1K, 58H 1 XD MEAN 1 STD.DEV.1 L MEAN 2 STD.DEV.2 /)	8029130
FKR = 1./FLOAT(K)	8029140
DO 9 I=1,N1	8029150
SUM1 = 0.	8029160
SUM2 = 0.	8029170
DO 13 J=1,K	8029180
SUM1 = SUM1 + DEN(I,J)	8029190
13 SUM2 = SUM2 + DEN(I,J)*DEN(I,J)	8029200
MEAN1 =SUM1* FKR	8029210
STD1=SQRT((SUM2*FKR - MEAN1*MEAN1)/FLOAT(K-1))	8 29220
SUM1=0	8029230
SUM2=0	8029240
L=0	8029250
DO 15 J=1,K	8029260
Q= DEN(I,J)-MEAN1	8029270
IF(ABS(Q).GT.3.*STD1) GO TO 15	8 29280
SUM1 = SUM1 + DEN(I,J)	8029290
SUM2 = SUM2 + DEN(I,J)*DEN(I,J)	8029300
L=L+1	8029310
15 CONTINUE	8029320
FLR =1./FLOAT(L)	8029330
MEAN2 = SUM1*FLR	8029340
STD2=SQRT((SUM2*FLR - MEAN2*MEAN2)/FLOAT(L-1))	8 29350
WRITE(6,120)I,X (I),MEAN1,STD1,L,MEAN2,STD2	8029360
120 FORMAT(1H ,1X,12,1X, 3F10.6,1X,12,1X,2F10.6)	8029370
Y(I)=MEAN2	8029380
9 CONTINUE	8029390
RETURN	8029400
END	8029410

\$IBFTC DISCR2 DECK	9029421
SUBROUTINE DISCR2 (A,AMEAN,ADEV)	9029430
COMMON/BITER/NO,K	9029440
DIMENSION A(20)	9029450
REAL MEAN1, MEAN2	9029460
FKR = 1./FLOAT(K)	9029470
SUM1 = 0.	9029480
SUM2 = 0.	9029490
DO 13 J=1,K	9029510
SUM1 = SUM1 + A(J)	9029520
13 SUM2 = SUM2 + A(J) *A(J)	9029530
MEAN1 =SUM1* FKR	9029540
STD1 = SQRT((SUM2*FKR - MEAN1*MEAN1)/FLOAT(K-1))	9 29550
SUM1=0	9029560
SUM2=0	9029570
L=0	9029580
DO 15 J=1,K	9029590
X=A(J)-MEAN1	9029600
IF(ABS(X).GT.3.*STD1) GO TO 15	9 29610
SUM1=SUM1+A(J)	9029615
SUM2 = SUM2 + A(J) *A(J)	9029620
L=L+1	9029630
15 CONTINUE	9029640
FLR =1./FLOAT(L)	9029650
MEAN2 = SUM1*FLR	9029660
STD2 = SQRT((SUM2*FLR - MEAN2*MEAN2)/FLOAT(L-1))	9 29670
AMEAN=MEAN2	9029680
ADEV=STD2	9029690
RETURN	9029700
END	9029710

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$IBFTC QUAD    DECK,DEBUG                                10029721
SUBROUTINE QUAD                                          10029730
COMMON/BNXF/XI,XO,XC,XTP,FPATH,S,NQUAD ,K,II           10029750
COMMON/BSTOSS/WSQ,VSQ,COSN,ALPHA                       10029755
COMMON/BNIF/IO,IC,ITP,PHID,USQO                       10029756
DIMENSION A(70),H(70)                                  10029790
REAL INTGRL                                              10029800
DATA (A(I),H(I),I=1,28)/                                10030050
1 7.74596669241483E-01, 5.55555555 55556E-01,-0.      E-00,10030060
1 8.888888888888889E-01, 8.61136311 94053E-01, 3.47854845137454E-01,10030070
1 3.39981043584856E-01, 6.52145154 62546E-01, 9.06179845938664E-01,10030080
1 2.36926885056189E-01, 5.38469310 05683E-01, 4.78628670499366E-01,10030090
1-0.      E-00, 5.68888888 88889E-01, 9.32469514203152E-01,10030100
1 1.71324492379170E-01, 6.61209386 66265E-01, 3.60761573048139E-01,10030110
1 2.38619186083197E-01, 4.67913934 72691E-01, 9.49107912342759E-01,10030120
1 1.29484966168870E-01, 7.41531185 99394E-01, 2.79705391489277E-01,10030130
1 4.05845151377397E-01, 3.81830050 05119E-01,-0.      E-00,10030140
1 4.17955183673469E-01, 9.60289856 97536E-01, 1.01228536290376E-01,10030150
1 7.96666477413627E-01, 2.22381034 53374E-01, 5.25532409916329E-01,10030160
1 3.13706645877887E-01, 1.83434642 95650E-01, 3.62683783378362E-01,10030170
1 9.68160239507826E-01, 8.12743883 15740E-02, 8.36031107326636E-01,10030180
1 1.80648160694857E-01, 6.13371432 00590E-01, 2.60610696402935E-01,10030190
1 3.24253423403809E-01, 3.12347077 40003E-01,-0.      E-00,10030200
1 3.30239355001260E-01, 9.73906528 17172E-01, 6.66713443086880E-02,10030210
1 8.65063366688985E-01, 1.49451349 50581E-01, 6.79409568299024E-01,10030220
1 2.19086362515982E-01, 4.33395394 29247E-01, 2.69266719309996E-01,10030230
1 1.48874338981631E-01, 2.95524224 14753E-01/      10030240
DATA (A(I),H(I),I=29,56)/                                10030250
1 9.78228658146057E-01, 5.56685671 61740E-02, 8.87062599768095E-01,10030260
1 1.25580369464905E-01, 7.30152005 74049E-01, 1.86290210927734E-01,10030270
1 5.19096129206812E-01, 2.33193764 91990E-01, 2.69543155952345E-01,10030280
1 2.62804544510247E-01,-0.      E-00, 2.72925086777901E-01,10030290
1 9.81560634246719E-01, 4.71753363 65120E-02, 9.04117256370475E-01,10030300
1 1.06939325995318E-01, 7.69902674 94305E-01, 1.60078328543346E-01,10030310
1 5.87317954286617E-01, 2.03167426 23066E-01, 3.67831498998180E-01,10030320
1 2.33492536538355E-01, 1.25233408 11469E-01, 2.49147045813403E-01,10030330
1 9.84183054718588E-01, 4.04840047 53160E-02, 9.17598399222978E-01,10030340
1 9.21214998377280E-02, 8.01578090 33310E-01, 1.38873510219787E-01,10030350
1 6.42349339440340E-01, 1.78145980 61946E-01, 4.48492751036447E-01,10030360
1 2.07816047536889E-01, 2.30458315 55135E-01, 2.26283180262897E-01,10030370
1-0.      E-00, 2.32551553 30874E-01, 9.86283808696812E-01,10030380
1 3.51194603317520E-02, 9.28434883 63574E-01, 8.01580871597600E-02,10030390
1 8.27201315069765E-01, 1.21518570 87903E-01, 6.87292904811685E-01,10030400
1 1.57203167158194E-01, 5.15248636 58154E-01, 1.85538397477938E-01,10030410
1 3.19112368927890E-01, 2.05198463 21296E-01, 1.08054948707344E-01,10030420
1 2.15263853463158E-01, 9.87992518 20485E-01, 3.07532419961170E-02,10030430
1 9.37273392400706E-01, 7.03660474 81080E-02/      10030440
DATA (A(I),H(I),I=57,70)/                                10030450
1 8.48206583410427E-01, 1.07159220 67172E-01, 7.24417731360170E-01,10030460
1 1.39570677926154E-01, 5.70972172 08539E-01, 1.66269205816994E-01,10030470
1 3.94151347077563E-01, 1.86161000 15562E-01, 2.01194093997435E-01,10030480
1 1.98431485327112E-01,-0.      E-00, 2.02578241925561E-01,10030490
1 9.89400934991650E-01, 2.71524594 17540E-02, 9.44575023073233E-01,10030500
1 6.22535239386480E-02, 8.65631202 87832E-01, 9.51585116824930E-02,10030510
1 1.575404408355003E-01, 1.24628971 55534E-01, 6.17876244402644E-01,10030520
1 1.49595988816577E-01, 4.58016777 57227E-01, 1.69156519395003E-01,10030530
1 2.81603550779259E-01, 1.82603415 44924E-01, 9.50125098376370E-02,10030540
1 1.89450610455068E-01/                                10030550
EQUIVALENCE (N,NQUAD)                                  10029810
XOFA(A)=XI+(XO-XI)*(1.+A)*.5                          10029820
200 INTGRL=0.0                                           10029830
      INDKT= MOD(N,2)+1                                  10029840
C      INDKT = 1, N IS EVEN                             10029850
C      INDKT = 2, N IS ODD                              10029860
      GO TO (204,210),INDKT                             10029870
204 MIN=(N+N)/4 -1                                       10029880
      MAX=(N*(N+2))/4 -2                                 10029890
      GO TO 215                                           10029900
210 MIN= (N*N-9)/4 +1                                    10029910
      MAX= (N*(N+2)-11)/4                                10029920
215 DO 220 I=1,2                                         10029930
      DO 220 J=MIN,MAX                                   10029940
      A(J)= -A(J)                                         10029950
      X=XOFA(A(J))                                        10029960
      TEST=USQO+PHI(X)                                    10029970
      IF(TEST.LE.0.) GO TO 1                             10029975
      F=SQRT(1.+VSQ/TEST)                                 10029976
220 INTGRL= INTGRL+H(J)*F                               10029980
      GO TO (250,225),INDKT                             10029990
225 X=XOFA(A(MAX+1))                                     10030000
      TEST=USQO+PHI(X)                                    10030010
      IF(TEST.LE.0.) GO TO 1                             10030015
      F=SQRT(1.+VSQ/TEST)                                 10030016
      INTGRL= INTGRL+H(MAX+1)*F                         10030020
250 INTGRL=.5*(XO-XI)*INTGRL                            10030030
      S=ABS(INTGRL)                                       10030035
      RETURN                                              10030040
1 CONTINUE                                              10
      S=0                                                  10030056
      RETURN                                              10030057
      END                                                  10030560

```


\$IBFTC PHI	DECK	11030571
FUNCTION PHI(Z)		11030580
COMMON/BRPHI/NDEG, B(20),NDPHI,ADPHI(20),NDDPHI		11030590
LI=NDEG+1		11030600
P=B(LI)*Z+B(NDEG)		11030610
DO 100 I=2, NDEG		11030620
LJ=LI-I		11030630
100 P=B(LJ)+Z*P		11030640
PHI=P		11030650
RETURN		11030660
END		11030670

\$IBFTC DPHI	DECK	12030681
FUNCTION DPHI(Z)		12030690
COMMON/BRPHI/NPHI,APHI(20),NDEG, B(20),NDDPHI		12030700
LI=NDEG+1		12030710
P=B(LI)*Z+B(NDEG)		12030720
DO 100 I=2, NDEG		12030730
LJ=LI-I		12030740
100 P=B(LJ)+Z*P		12030750
DPHI=P		12030760
RETURN		12030770
END		12030780

\$IBFTC DENS	DECK	13 30791
FUNCTION DENS(Z)		13 30800
COMMON/BCHEB/X(43),B(21),ERROR		13030810
COMMON/BCHEB2/LI		13030815
NDEG=LI-1		13030820
P=B(LI)		13 30830
DO 100 I=1,NDEG		13 30840
LJ=LI-I		13030870
100 P=B(LJ)+Z*P		13030880
DENS=P		13 30890
RETURN		13030900
END		13030910

\$IBFTC MINPHI	DEBUG,DECK	14 00010
SUBROUTINE MINPHI		14 00020
COMMON/BMIN/XMIN,PHIMIN,IMIN,TPHID(33),TPHIX(1026),A,B,C,DELX,EN		14 00030
COMMON/BCHEB/N1,X(21),DUMMY(43)		14 00040
DATA N/1024/		14 00050
PHIMIN = 0		14 00060
IMIN=1		14 0065
EN=N		14 00070
DELX = 1./FLOAT(N)		14 00080
DO 1 I=1,N1		14 00090
1 TPHID(I) = PHIX(I)		14 00100
M = N+1		14 00110
TPHIX(1) = 0		14 00120
DO 2 I=2,M		14 00130
U=DELX*FLOAT(I-1)		14 0140
TPHIX(I) = PHIX(U)		14 00150
IF (PHIMIN.LT.TPHIX(I)) GO TO 2		14 00160
PHIMIN = TPHIX(I)		14 00170
IMIN = I		14 00180
2 CONTINUE		14 00190
XMIN=DELX*FLOAT(IMIN-1)		14 0200
DEBUG XMIN,PHIMIN		14 00270
RETURN		14 00320
END		14 00350

```

$IBFTC XIC      DECK
SUBROUTINE XIC
COMMON/BSTOSS/VSQ,VSQ,COSN,ALPHA
COMMON/BNIF/IO,IC,ITP,PHIO,USQO
COMMON/BNXF/XO,XF,XC,XTP,FPATH,S,NQUAD,K,II
COMMON/BMIN/XMIN,PHIMIN,IMIN,TPHID(33),TPHIX(1026),A,B,C,DELX,EN
DIMENSION I(3),DSX(3)
COMMON KNTR,N(11)
KNTR=KNTR+1
I(1)=IO
IFF=EN*XF+1.5
F=FPATH
Q=VSQ/USQ
DSX(1)=SQRT(1.+Q)
10 M=(IFF-I(1))/4
IF(IABS(M).EQ.0) GO TO 30
MM=ALOG10(Q)
MN=2*(4-MM)
IF(M.GT.MN) M=MN
IF(MM.GT.4) M=1
EM=M
H=ABS(EM*DELX/3.)
DO 11 J=2,3
I(J)=I(J-1)+M
IJ=I(J)
Q=USQO+TPHIX(IJ)
Q=VSQ/Q
IF(Q.LT.0.) GO TO 61
DSX(J)=SQRT(1.+Q)
SS=H*(DSX(1)+4.*DSX(2)+DSX(3))
Y=F-SS
IF(Y.LT.0.) GO TO 20
I(1)=I(3)
DSX(1)=DSX(3)
F=Y
GO TO 10
20 IFF=I(3)
GO TO 10
30 M=(IFF-I(1))/2
IF(IABS(M).EQ.0) GO TO 60
I(2)=I(1)+M
I2=I(2)
Q=USQO+TPHIX(I2)
DSX(2)=SQRT(1.+VSQ/Q)
EM=M
H=ABS(EM*DELX*.5)
SS=H*(DSX(1)+DSX(2))
Y=F-SS
IF(Y.LT.0.) GO TO 40
I(1)=I(2)
DSX(1)=DSX(2)
F=Y
GO TO 30
40 IC=I(2)
50 XC=DELX*FLOAT(IC-1)
RETURN
60 IC=IFF
GO TO 50
61 IC=IO
RETURN
END

```

```

$IBFTC XITP      DECK
SUBROUTINE XITP
COMMON/BSTOSS/VSQ,VSQ,COSN,ALPHA
COMMON/BNXF/XO,XF,XC,XTP,FPATH,S,NQUAD,K,II
COMMON/BMIN/XMIN,PHIMIN,IMIN,TPHID(33),TPHIX(1026),A,B,C,DELX,EN
COMMON/BNIF/IO,IC,ITP,PHIO,USQO
I1=EN*XO+1.5
I2=IMIN
1 M=(I2-I1)/2
IF(M.EQ.0) GO TO 5
I=I1+M
TEST=USQO+TPHIX(I)
IF(TEST)2,4,3
2 I2=I
GO TO 1
3 I1=I
GO TO 1
4 ITP=I
GO TO 6
5 ITP=I1
6 XTP=DELX*FLOAT(I-1)
DIF(K.EQ.1.AND.II.LE.5) DEBUG ITP,USQO,TPHIX(ITP-1),TPHIX(ITP),
TPHIX(ITP+1)
RETURN
END

```

\$IBFTC CHEBY DECK	17031301
SUBROUTINE CHEBY(MOVE)	17031310
C	17 31315
C CHEBYSCHV POLYNOMIAL FIT TO SAMPLE DENSITIES FROM ITER SUBROUTINE	17 31316
C	17 31317
DIMENSION TRNMAT(21,21),X(21),SUB(11,11),	17031340
2 UP(11),UPP(11),APP(11),AP(11),ASUBN(21),COEFS(21),Y(21)	17031350
COMMON/BCHEB/ N1,X,Y,COEFS,EPS	17031360
COMMON/BPHI/NPHI, A(20),NDPHI, AI(20),NDDPHI	17031370
COMMON/BCHEB2/N2	17031370
DOUBLE PRECISION PI,THETA,PION	17 31378
DATA PI/3.1415926535897932/	17 31379
DATA TRNMAT(1,1),TRNMAT(1,2),TRNMAT(2,2)/1.,-1.,2./	17 31380
EQUIVALENCE (NPHI,N1)	17031400
GO TO (10,100),MOVE	17031410
10 N=N1-1	17031420
NPN = N+N	17031430
NPLUS2 = N+2	17031440
M = N/2	17031450
MP1 = M+1	17031460
MP2 = M+2	17031470
EN=N	17 31480
PION=PI/EN	17 31490
DO 15 I=1,NPHI	17031500
THETA = (1. - FLOAT(I-1)/EN)*PI	17 31510
X(I)=DCOS(THETA)	17 31520
17 X(I)=(X(I)+1.)*.5	17 31540
15 CONTINUE	17031550
20 DO 25 I=3,NPHI	17031570
TRNMAT (1,I) = -TRNMAT(1,I-1)	17031580
DO 25 J=2,I	17031590
25 TRNMAT(J,I) = 4.*TRNMAT(J-1,I-1)-2.*TRNMAT(J,I-1)-TRNMAT(J,I-2)	17031600
40 L=MP1	17031660
DO 70 I=1,L	17031670
DO 70 J=1,L	17031680
70 SUB(I,J) = DCOS(FLOAT((J-1)*(I-1)) * PION)	17 31690
RETURN	17 31700
100 NPHI = NPHI	17031710
UP(1) = Y(NPHI)-Y(1)	17031720
UPP(1) = Y(NPHI)+Y(1)	17031730
MOG=M-1	17031740
DO 104 I=1,MOG	17031750
NPHI1 = NPHI-I	17031760
UPP(I+1) = (Y(NPHI1)+Y(I+1))*2.0	17031770
104 UP(I+1) = (Y(NPHI1)-Y(I+1))*2.0	17031780
UPP(MPHI) = 2.0*Y(MPHI)	17031790
DO1 I=1,L,2	17031810
APP(I)=0.	17031820
AP(I)=0.	17031830
DO 2 J=1,L,2	17031840
2 APP(I)=APP(I)+SUB(I,J)*UPP(J)	17031850
DO 1 J=2,L,2	17031860
1 AP(I) =AP(I) + SUB(I,J)*UPP(J)	17031870
DO 3 I=2,L,2	17031880
AP(I)=0.	17031890
APP(I)=0.	17031900
DO 4 J=1,L,2	17031910
4 APP(I)=APP(I)+SUB(I,J)* UP(J)	17031920
DO 3 J=2,L,2	17031930
3 AP(I) =AP(I) + SUB(I,J)* UP(J)	17031940
DO 130 I=1,MP1	17031970
129 ASUBN(I) =(APP(I)+AP(I))/EN	17031980
INDICE= NPLUS2-I	17031990
130 ASUBN(INDICE)=0APP(I)-AP(I))/EN	17032000
ASUBN(1) = ASUBN(1)/2.0	17032010
ASUBN(NPHI) = ASUBN(NPHI)/2.0	17032020
DO 135 I=1,NPHI	17032030
IF(ABS(ASUBN(I)) -EPS) 133,135,135	17032050
133 ASUBN(I)=0.0	17032060
135 CONTINUE	17032070
DO 140 I=1,NPHI	17032090
COEFS(I) = 0.	17032100
DO 140 J=1,N2	17032110
140 COEFS(I) = COEFS(I)+TRNMAT(I,J)*ASUBN(J)	17032120
L=N1+1	17032140
11 L=L-1	17032150
IF(COEFS(L).EQ.0.) GO TO 11	17032160
NDDPHI=L-1	17032170
1000 RETURN	17032260
END	17032270

\$IBFTC COEF	DECK	19	11
	SUBROUTINE COEF(MODE)	19	20
	COMMON/BCHEB2/N2	19	24
	COMMON/8PHI/NPHI,APHI(20),NDPHI,ADPHI(20),NDEN	19	25
	COMMON/BCHEB/N1,X(42),COEFS(22)	19	26
	COMMON/BMAIN/ CONST,VOLT(20),CURRNT(20)	19	00027
	DATA KNTR/0/	19	00028
	GO TO (1,2,3),MODE	19	30
C		19	40
C	MODE 1 = READ INITIAL APHI(2),N1,COEFS	19	45
	1 CALL BCREAD(X(41),COEFS(11))	19	50
	APHI(2)= X(41)	19	54
	NDPHI=X(42)	19	55
	RETURN	19	56
C		19	60
C	MODE 2 = COMPUTE COEFFICIENTS OF PHI AND DPHI	19	65
	2 IF(KNTR.NE.0) NDPHI=N2	19	00070
	NPHI=NDPHI + 1	19	75
	NDEN =NDPHI - 1	19	80
	APHI(2)=VOLT(20)	U9	85
	DO 20 I=1,NDPHI	19	90
	APHI(I+2) = CONST*COEFS(I)/FLOAT(I*(I+1))	19	92
	20 APHI(2)=APHI(2)-APHI(I+2)	U9	94
	IF(KNTR.EQ.0) APHI(2)=A	19	96
	KNTR=1	19	98
	DO 21 I=1,NPHI	19	100
	21 ADPHI(I)= APHI(I+1)*FLOAT(I)	19	105
	RETURN	19	110
C		19	120
C	MODE 3 = PRINT COEFS	19	125
C	PUNCH APHI(2),N1,COEFS	19	126
	3 WRITE(6,30)(COEFS(I),I=1,N1)	19	130
	30 FORMAT(1H0, 5HCOEFS/1H ,8F15.6/1H ,3F15.6)	19	00135
	X(41)=APHI(2)	19	00140
	X(42)=N2	19	00145
	CALL BCDUMP(X(41),COEFS(11))	19	00146
	RETURN	19	150
	END	19	155

\$IBFTC PLOT	DECK	20	00011
	SUBROUTINE PLOT	20	00020
C		20	00023
C	PLOTS OF FINAL DENSITY AND POTENTIAL DISTRIBUTIONS	20	00024
	COMMON/8ITER/NO,KI	20	00025
	COMMON/BCHEB/N1,U(21),V(21),COEFS(21),ERROR	20	00030
	COMMON/8PHI/NPHI,APHI(20),NDPHI,AB(21)	20	00040
	COMMON/8STOSS/NSQ,VSQ,COSN,ALPHA	20	00046
	COMMON/BMAIN/ CONST,VOLT(20),CURRNT(20)	20	00045
	DIMENSION PD(11),PP(11),X1(26),X2(26),D(26),PH(26)	20	00050
	DATA PD/26.,0.,5.,10.,0.,2.,-20000.,500.,4.,0.,1./	20	00060
	DATA PP/26.,0.,5.,10.,0.,5.,-200.,4.,4.,0.,1./	20	00070
	DO 1 I=1,26	20	00080
	X1(I) = .04 * FLOAT(I-1)	20	00090
	X2(I) = X1(I)	20	00100
	D(I)=-DENS(X1(I))	20	00110
	1 PH(I)= - PHI(X1(I))	20	00120
	PP(7)= AINT(PH(26))-1.	20	00125
	PP(7)=10.*PP(7)	20	00126
	CALL SORTXY(D,X1,26)	20	00130
	CALL SORTXY(PH,X2,26)	20	00140
	WRITE(6,2)	20	00150
	2 FORMAT(2HPT, 50X,30HELECTRON DENSITY DISTRIBUTION)	20	00160
	CALL PLOTXY(D,X1,118,PD)	20	0017
	WRITE(6,3)APHI(2),CONST,ALPHA,NO,N1,KI	20	00180
	3 FORMAT(2HPL,20X, 29HAPHI(2),CONST,ALPHA,NO,N1,KI/ ,F5.2,1H,,F7.2,	20	00190
	11H,,E10.1,1H,, I6,1H,,I2,1H,,I2)	20	00200
	WRITE(6,4)	20	00210
	4 FORMAT(2HPT, 55X,22HPOTENTIAL DISTRIBUTION)	20	00220
	CALL PLOTXY(PH,X2,118,PP)	20	00230
	WRITE(6,5)APHI(2),CONST,ALPHA,NO,N1,KI	20	00240
	5 FORMAT(2HPL,20X, 29HAPHI(2),CONST,ALPHA,NO,N1,KI/ ,F5.2,1H,,F7.2,	20	00250
	11H,,E10.1,1H,, I6,1H,,I2,1H,,I2)	20	00260
	RETURN	20	00270
	END	20	00280

\$IBFTC CUMVEL DECK	21 00010
SUBROUTINE CUMVEL	21 00020
COMMON/BVEL/VEL(1024)	21 00030
DATA NMC/1024/	21 00035
DELX=1./FLOAT(NMC)	21 00040
DO 1 I=1,NMC	21 00050
X=DELX*(FLOAT(I)-1)+.5)	21 00060
1 VEL(I)=-ALOG(X)	21 00070
RETURN	21 00080
END	21 00090

\$IBFTC QUADGM DECK	
SUBROUTINE QUADGM	
C MODIFIED GAUSS'MEHLER QUADRATURE	GMQU0030
C NUMERICAL INTEGRATION OF FOFX(X)/SQRT(X-X0) FROM X0 TO XF	GMQU0040
COMMON/BNIF/IO,IC,ITP,PHIO,USQO	
COMMON/BNXF/XF,XI,XC,X0 ,FPATH,S,NQUAD ,K,II	
COMMON/BSTOSS/USQ,VSQ,COSN,ALPHA	
DIMENSION Y(33),A(33)	GMQU0050
REAL INTGRL	GMQU0060
DATA N/5/	GMQU0062
DATA (Y(I),A(I),I=1,33)/	GMQU0070
1 0.56939116E-01, 0.93582787E-00, 0.43719785E-00, 0.72152315E-00,	GMQU0080
1 0.86949939E-00, 0.34264898E-00, 0.33648268E-01, 0.72536757E-00,	GMQU0090
1 0.27618431E-00, 0.62741329E-00, 0.63467748E-00, 0.44476207E-00,	GMQU0100
1 0.92215661E-00, 0.20245707E-00, 0.22163569E-01, 0.59104845E-00,	GMQU0110
1 0.18783157E-00, 0.53853344E-00, 0.46159736E-00, 0.43817273E-00,	GMQU0120
1 0.74833463E-00, 0.29890270E-00, 0.94849393E-00, 0.13334269E-00,	GMQU0130
1 0.15683407E-01, 0.49829409E-00, 0.13530001E-00, 0.46698507E-00,	GMQU0140
1 0.34494238E-00, 0.40633485E-00, 0.59275013E-00, 0.32015666E-00,	GMQU0150
1 0.81742801E-00, 0.21387865E-00, 0.96346128E-00, 0.94350673E-01,	GMQU0160
1 0.11675872E-01, 0.43052771E-00, 0.10183270E-00, 0.41039693E-00,	GMQU0170
1 0.26548116E-00, 0.37107680E-00, 0.47237154E-00, 0.31440633E-00,	GMQU0180
1 0.68426202E-00, 0.24303714E-00, 0.86199133E-00, 0.16031617E-00,	GMQU0190
1 0.97275575E-00, 0.70238921E-01, 0.90273770E-02, 0.37890122E-00,	GMQU0200
1 0.79300560E-01, 0.36520683E-00, 0.20977937E-00, 0.33831304E-00,	GMQU0210
1 0.38177105E-00, 0.29919198E-00, 0.57063582E-00, 0.24925794E-00,	GMQU0220
1 0.74931738E-00, 0.19031702E-00, 0.89222197E-00, 0.12450705E-00,	GMQU0230
1 0.97891421E-00, 0.54304919E-01/	GMQU0240
FOFX(X,Y)=SQRT(ABS(X-X0) *(1.+VSQ/Y))	GMQU0242
XOFY(Y)=X0+(XF-X0)*Y	GMQU0250
INTGRL=0.	GMQU0260
MIN=N*(N-1)/2 -2	GMQU0270
MAX=MIN+N-1	GMQU0280
DO 210 J=MIN,MAX	GMQU0290
X=XOFY(Y(J))	GMQU0300
Z=USQO+PHI(X)	GM 0310
IF(Z.LE.0.) GO TO 211	GM 0312
F=FOFX(X,Z)	GM 0314
210 INTGRL=INTGRL+A(J)*F	GMQU0320
INTGRL=SQRT(ABS(XF-X0))*INTGRL	GMQU0330
S=ABS(INTGRL)	GMQU0332
RETURN	GMQU0340
211 S=0	GMQU0342
RETURN	GMQU0344
END	GMQU0350

APPENDIX D

SYMBOLS

[All dimensioned variables in cgs-esu units.]

a_k	coefficients, eq. (24)	ℓ_c	dimensionless path length for collision, eq. (2)
C	dimensionless constant, eqs. (6), (8), and (10)	m	mass of electron, eq. (5)
c_j	coefficients, eq. (25)	N_c	number of electrons striking collector, eq. (22)
$E[\]$	expectation value of $[\]$, eq. (A4)	N_o	total number of histories, eq. (22)
e	electronic charge, eq. (7)	n	dimensionless electron density, eq. (6)
$F_u(V), F_V(u)$	marginal distributions, eqs. (12) and (13)	\hat{n}	electron density, eq. (7)
$f(u)$	probability distribution function, eq. (A2)	n_o	electron density of emitted flux, eq. (7)
$f(u, V)$	dimensionless velocity distribution function, eq. (4)	$P[\]$	probability of $[\]$, appendix A
$g(\mathbf{X})$	function of random variable \mathbf{X} , appendix A	$p(r)$	uniform probability distribution function, eq. (A7)
\bar{g}_N	sample mean of $g(x)$, eq. (A20)	R_k	uniformly distributed random numbers
J	electron current to collector, eq. (22)	s	path length, eq. (3)
J_o	electron emission current, eqs. (8) and (22)	T	emitter temperature, eq. (5)
k	Boltzmann's constant, eq. (5)	U	random variable, appendix A
L	interelectrode separation, eq. (2)	u	dimensionless x-component of velocity, eqs. (5) and (9)
ℓ	dimensionless path length, eq. (3)	u_o	initial velocity, eq. (20)
		V	dimensionless velocity component transverse to the x-direction
		$\mathcal{V}(x)$	potential distribution

v_o	initial velocity of monoenergetic emission, eq. (9)	θ^*	capture angle, eq. (34)
v_x, v_y, v_z	components of velocity	λ	mean free path, eq. (3)
X, Y	random variables, appendix A	$\hat{\sigma}_g$	theoretical standard deviation, eq. (A20)
x	spatial coordinate, eq. (7)	σ_g	sample deviation, appendix A
y	dimensionless spatial coordinate, eq. (7)	σ_J	standard deviation of current to collector
y_c	location of collision, eq. (29)	φ	dimensionless potential distribution: thermionic emission, eq. (7); monoenergetic emission, eq. (9)
y_o	location of last event, eq. (29)	Ω	solid angle, eq. (1)
α	dimensionless reciprocal mean free path, eq. (3)	$[]$	integral value
Γ_c	flux to collector	$\{ \}$	sequence of terms $\{ \}$, appendix A
Γ_o	emitted flux		
θ	scattering angle, eq. (1)		

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